

Accurate Full Spectrum Test Robust to Simultaneous Non-coherent sampling and Amplitude clipping

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Iowa State University, Ames, IA, USA

Acknowledgments

- Semiconductor Research Corporation
- Texas Instruments Inc.
- National Science Foundation

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- To perform accurate spectral testing
 - WITHOUT requiring Coherent sampling
 - WITHOUT requiring precise amplitude control
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- Applications
 - Analog Mixed Signal Built-in Self Test (AMS-BIST)
 - Low cost spectral testing

Outline

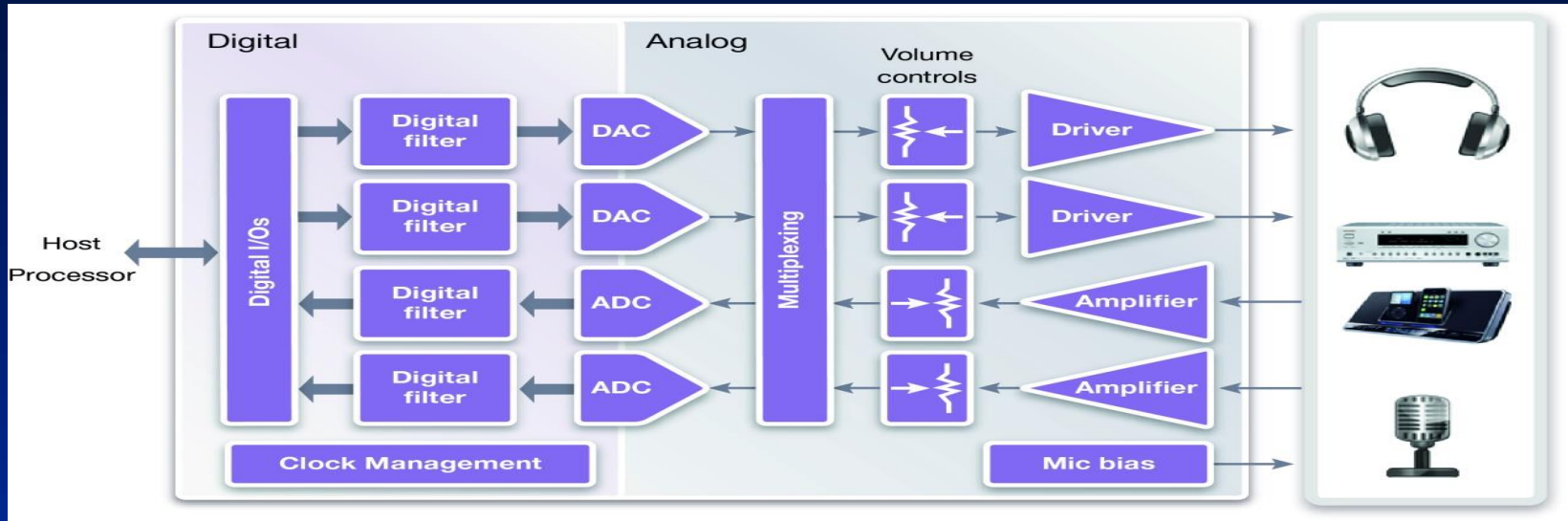
- Motivation and Spectral testing Background
- Proposed spectral testing method
 - Fundamental Estimation, Removal And Residue Interpolation (FERARI)
 - Spectral Testing Algorithm
- Simulation Results
- Measurement Results
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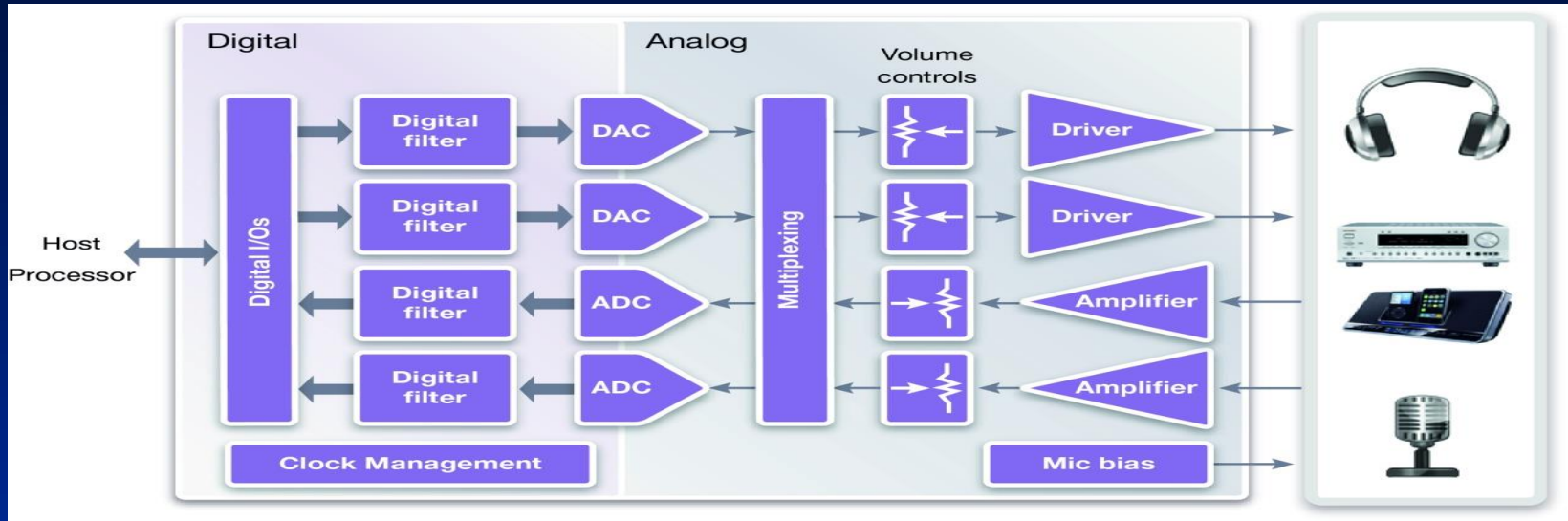
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Emerging products have embedded data converters



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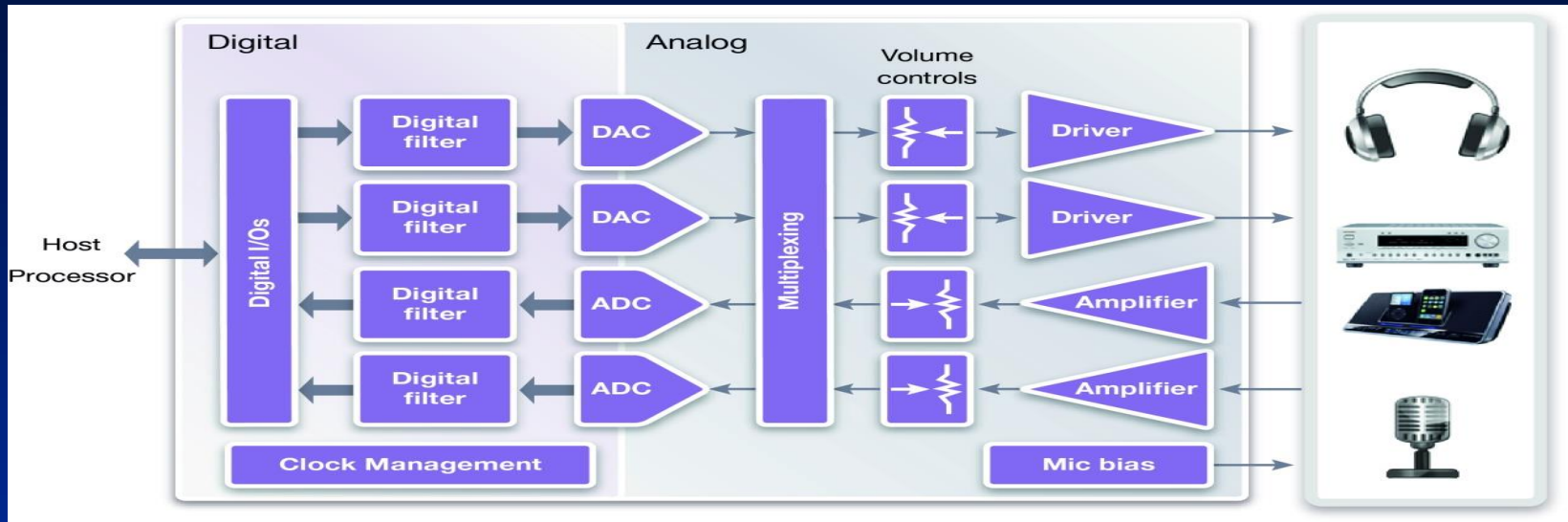
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Challenging to de-embed and test block cost effectively

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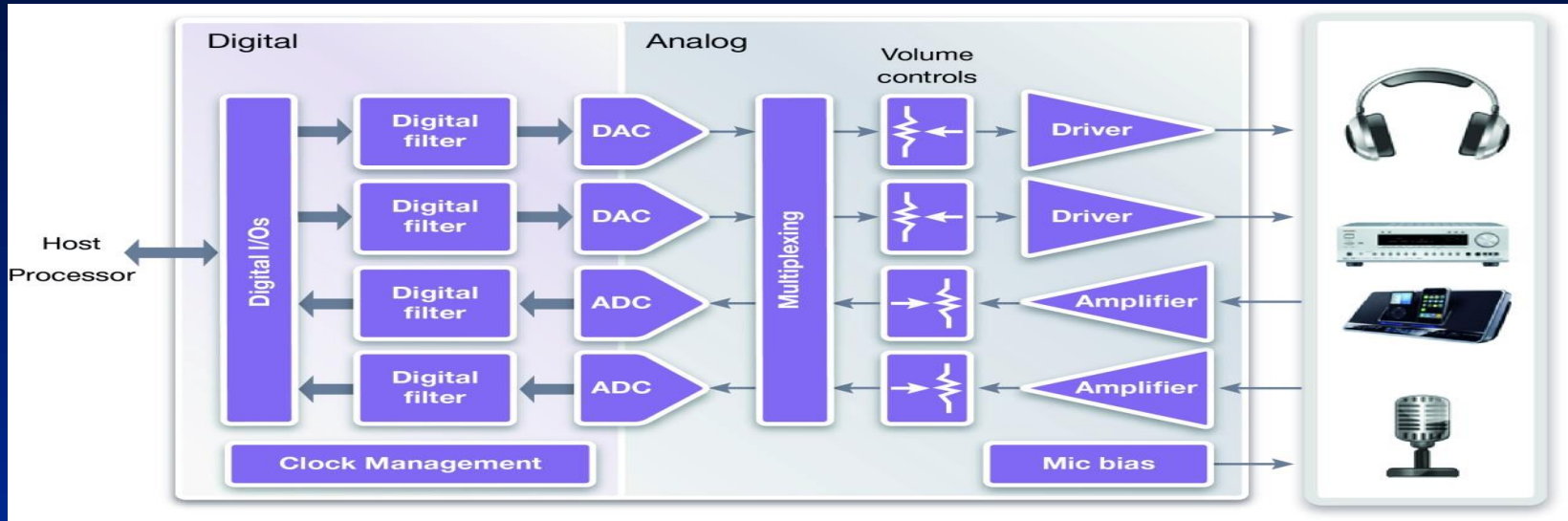
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- Conventional testing → precise amplitude and frequency control
- Designing high end test circuitry on-chip is challenging
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Require new test methods that relax stringent conditions

Spectral Testing

Used to test the frequency characteristics of a device under test (DUT)

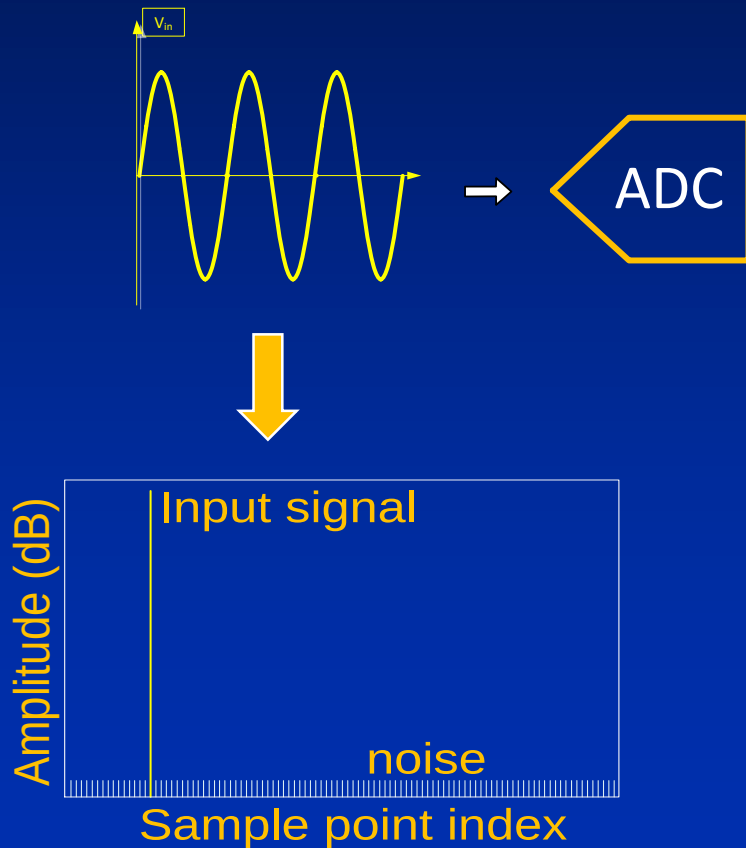
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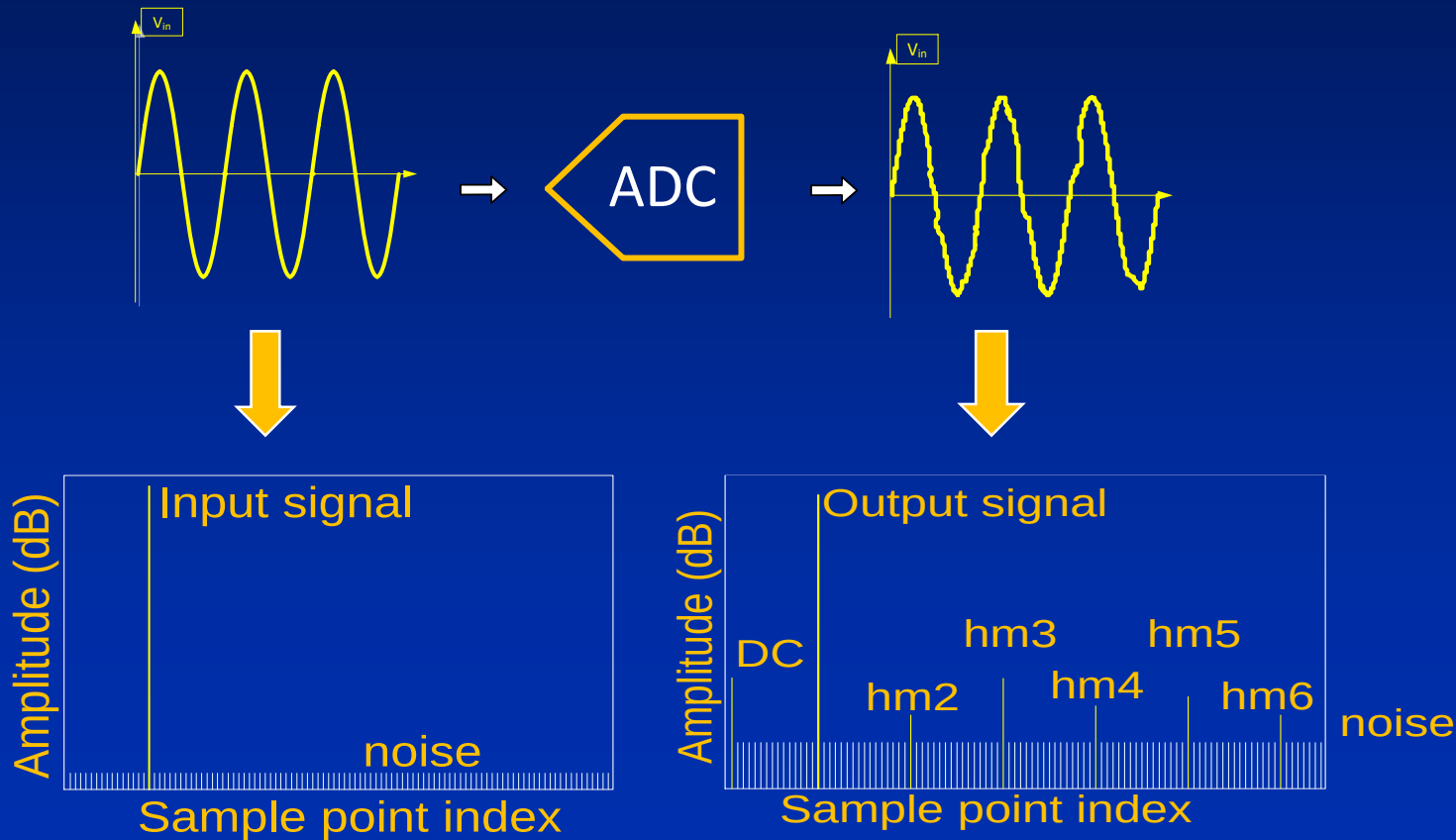
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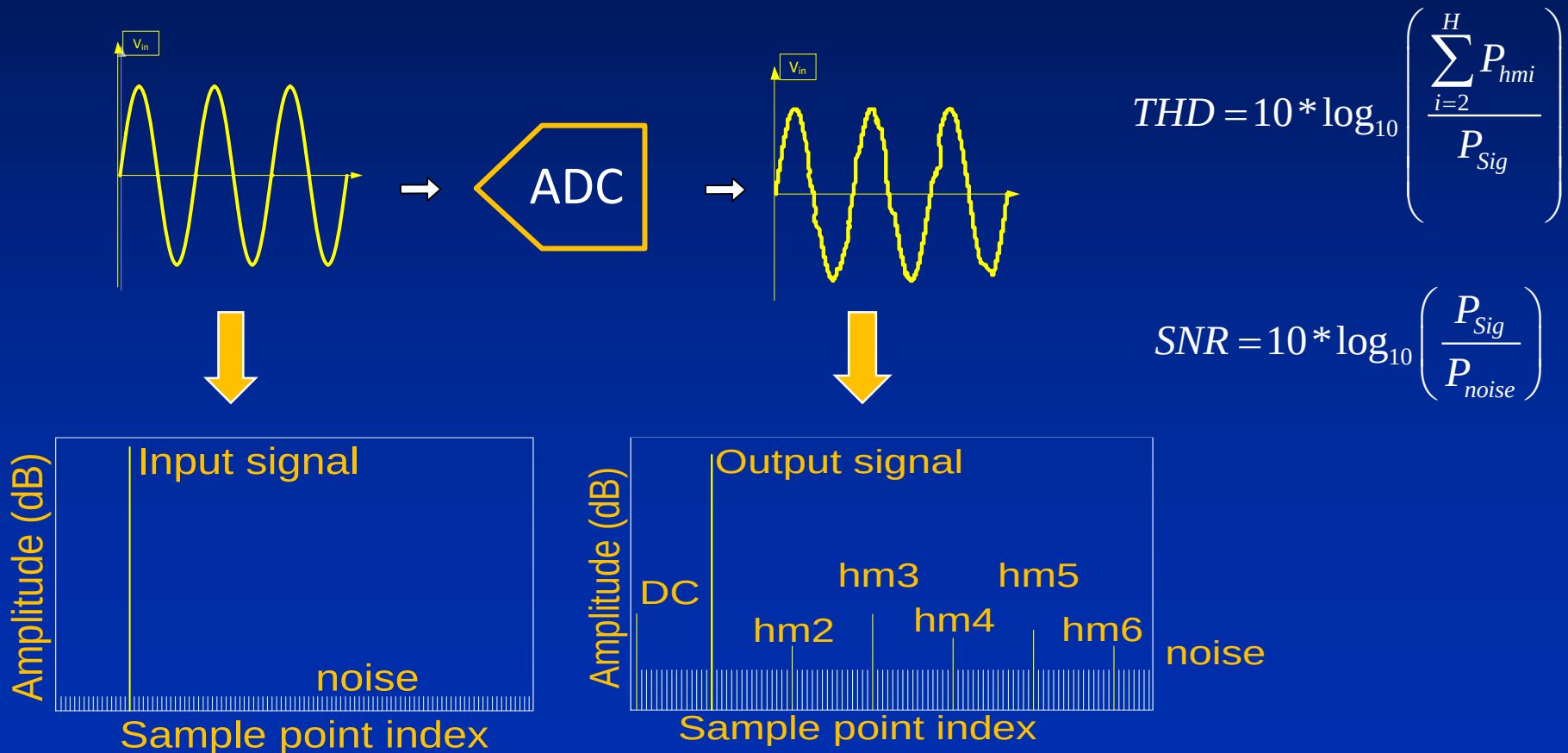
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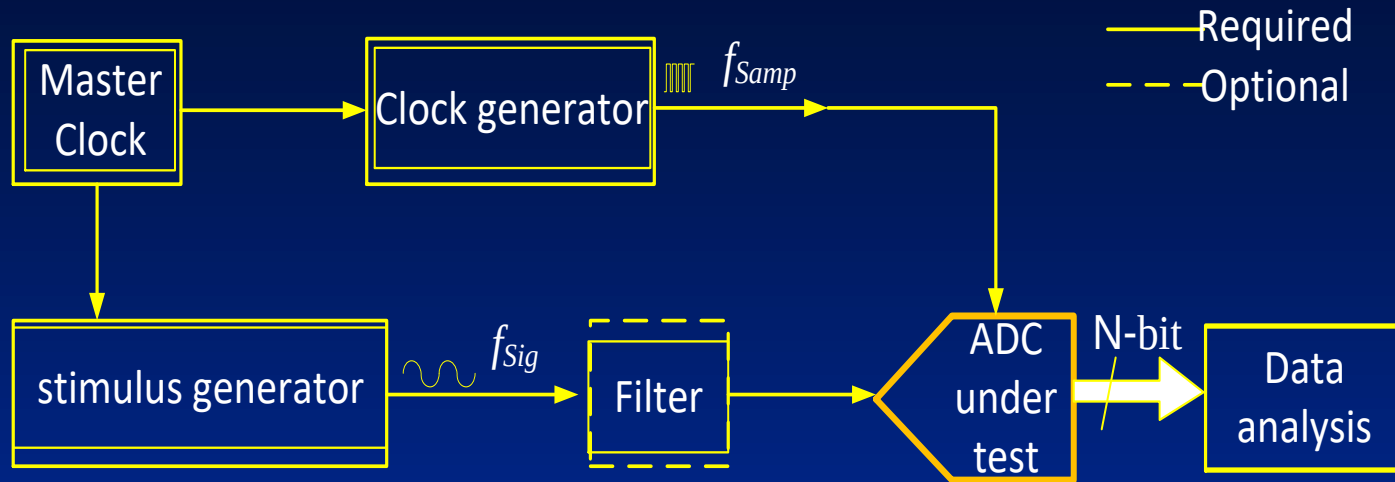


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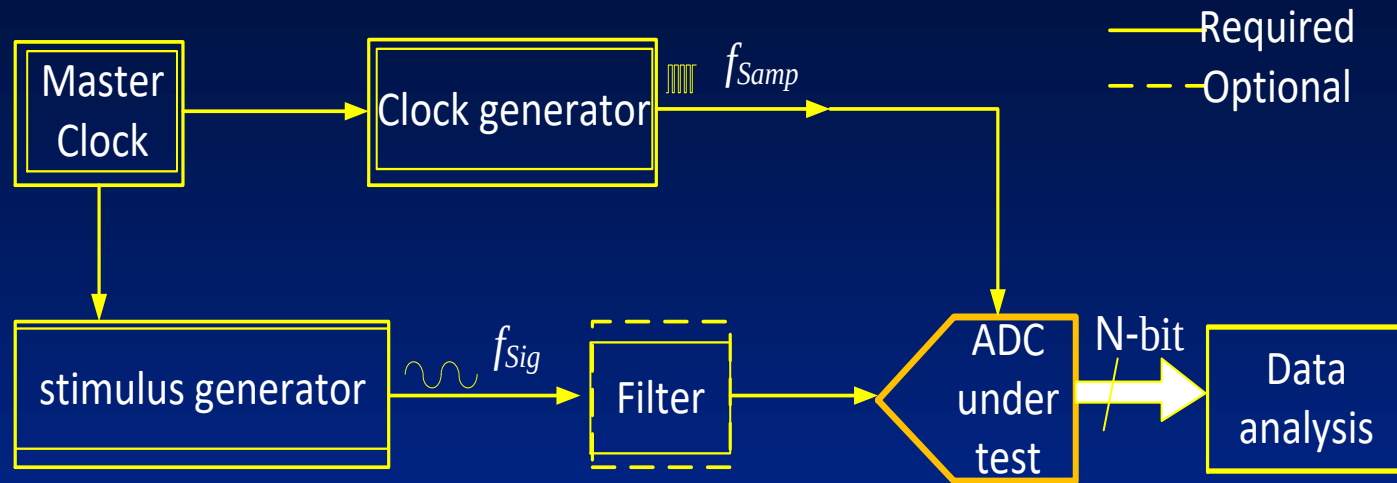
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IEEE Standard method



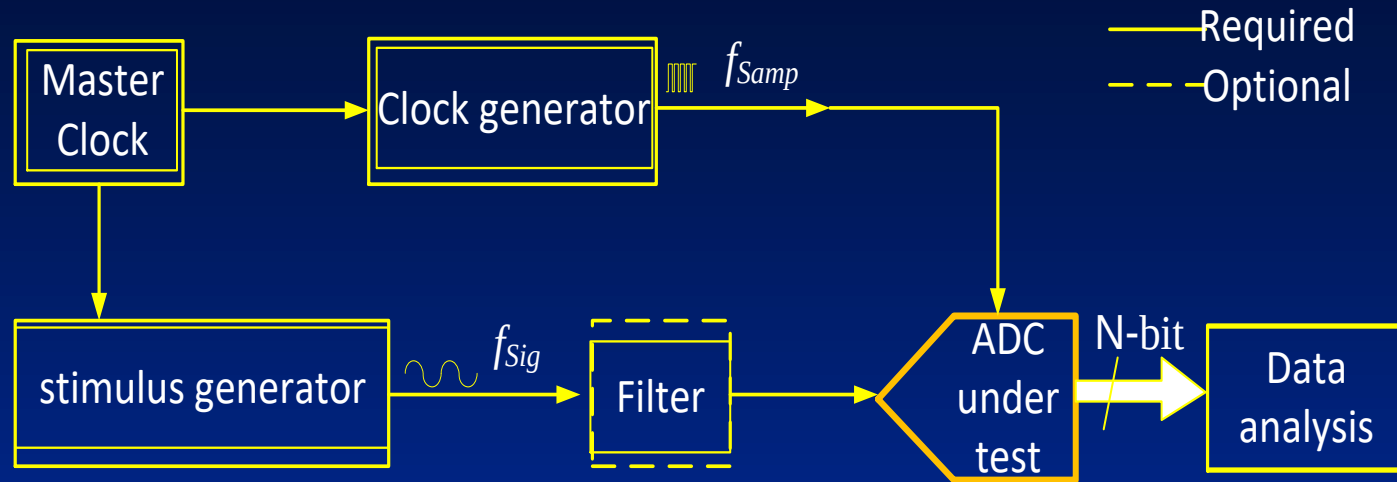
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Challenging Requirements

- Input signal about 3-4 bits more pure than ADC

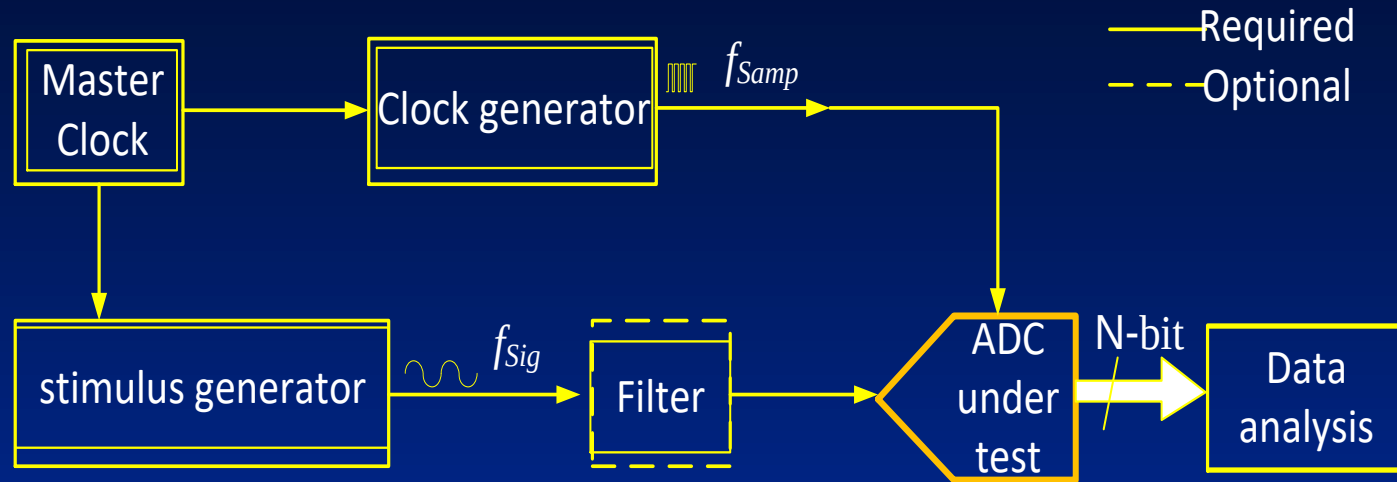
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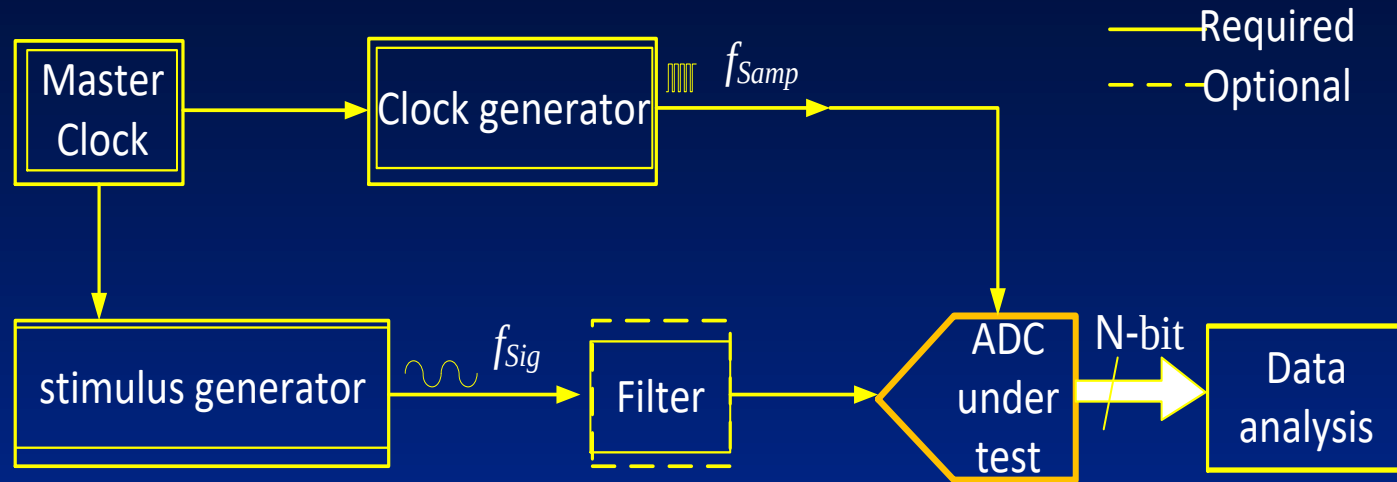
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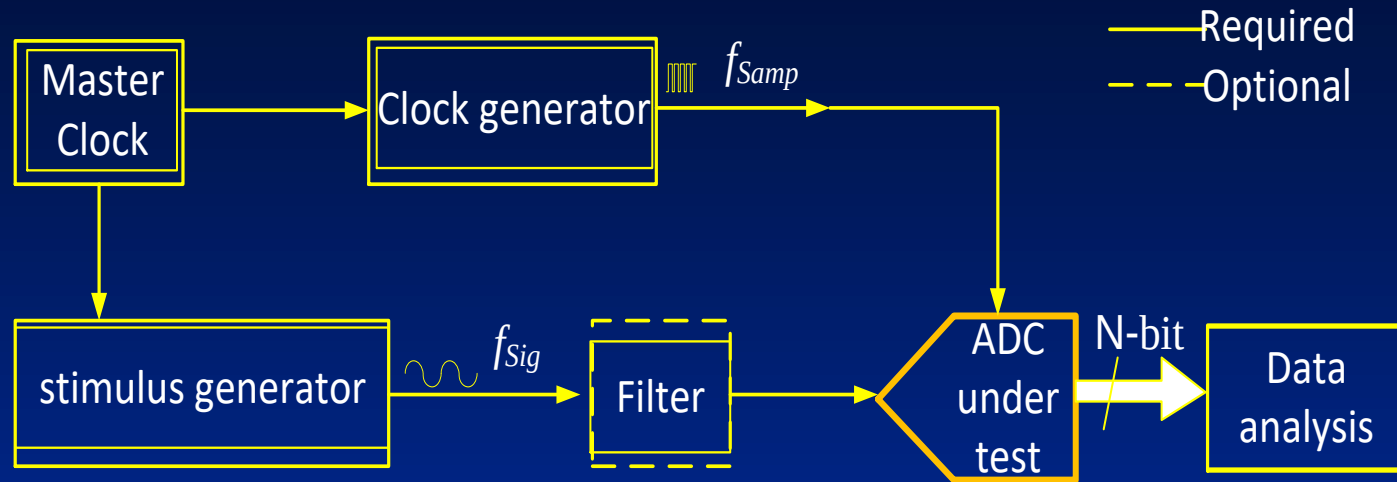
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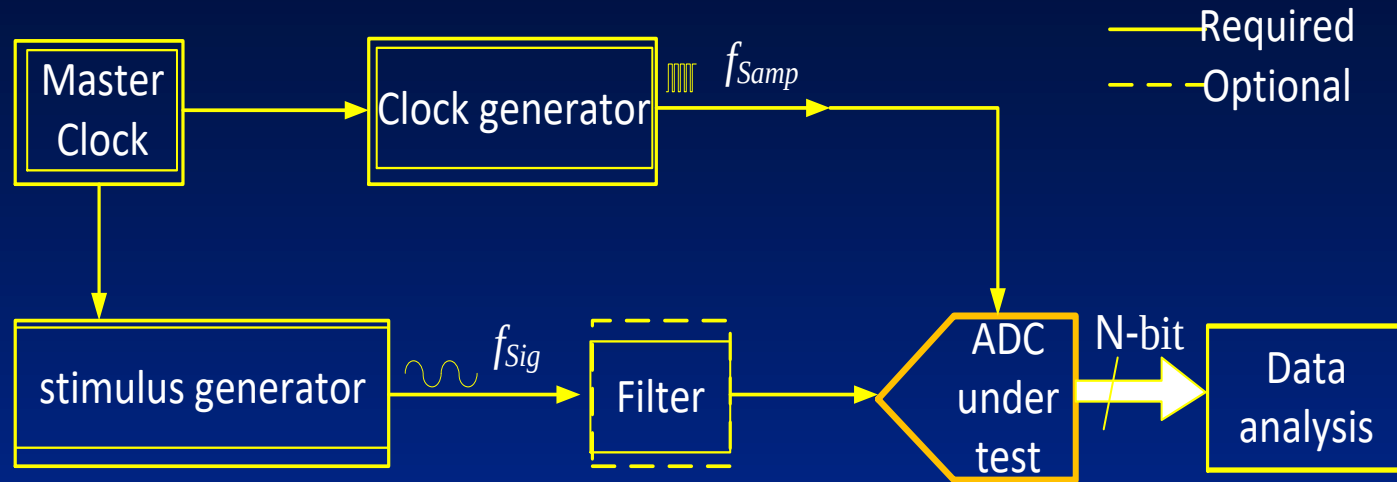
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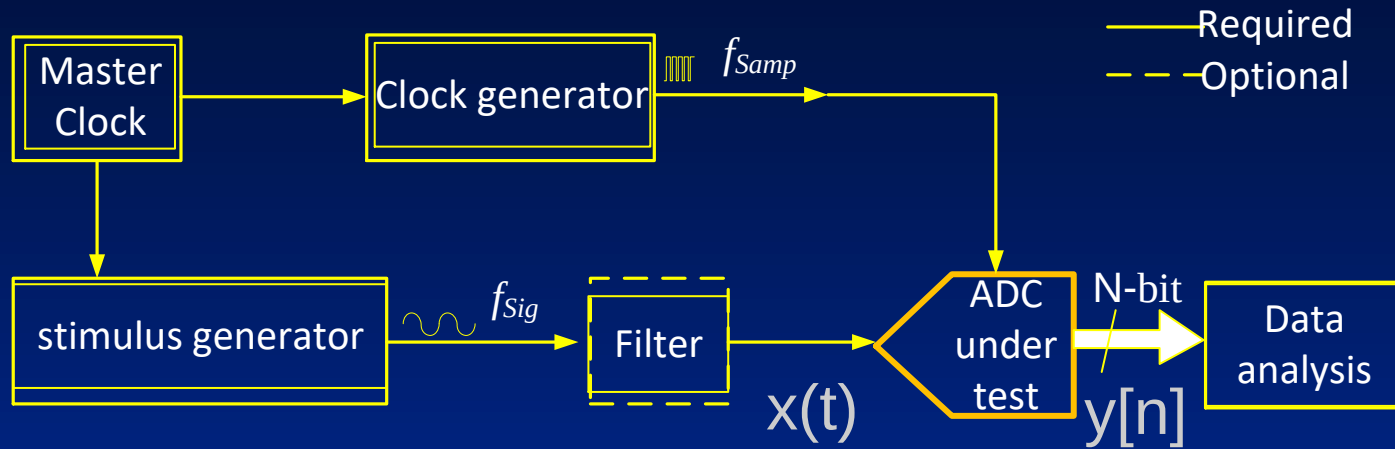
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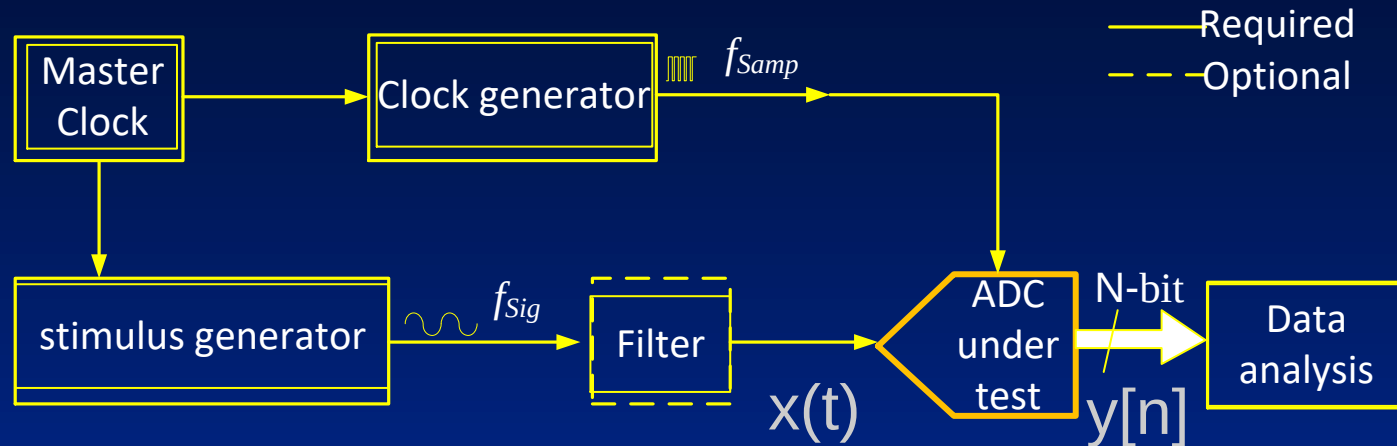
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IEEE Standard test method



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Notations

- $x(t)$: Analog input signal

- $x(t) = A \sin(2\pi f_{Sig} t)$

- $y[n]$: Analog interpretation of digital output of ADC,
 $n = 0, 1, 2, \dots, M-1$.

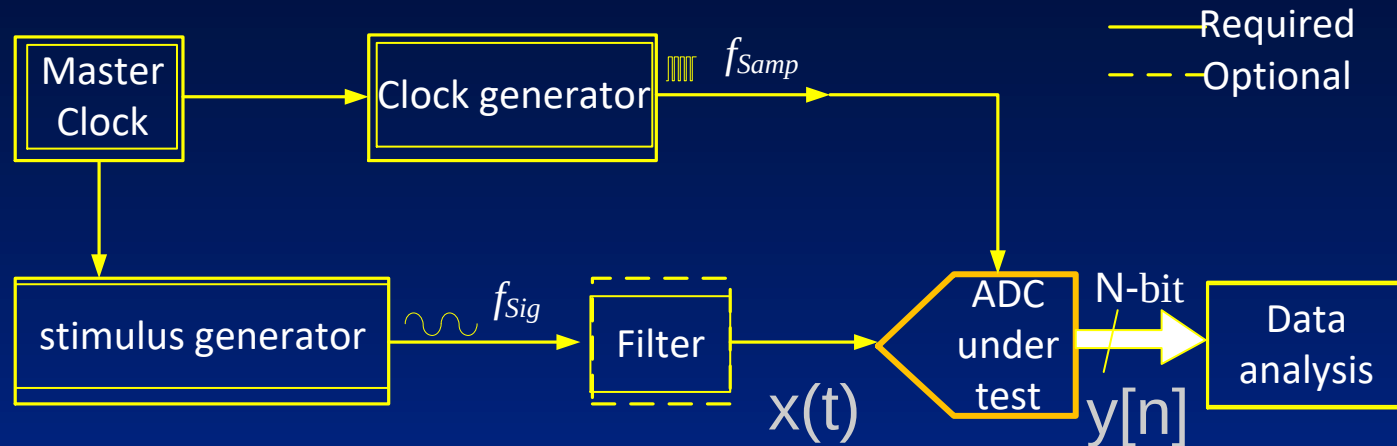
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$$J = M \cdot f_{Sig} / f_{Samp}$$

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Sampling (Coherent vs Non-coherent)

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M sampled points

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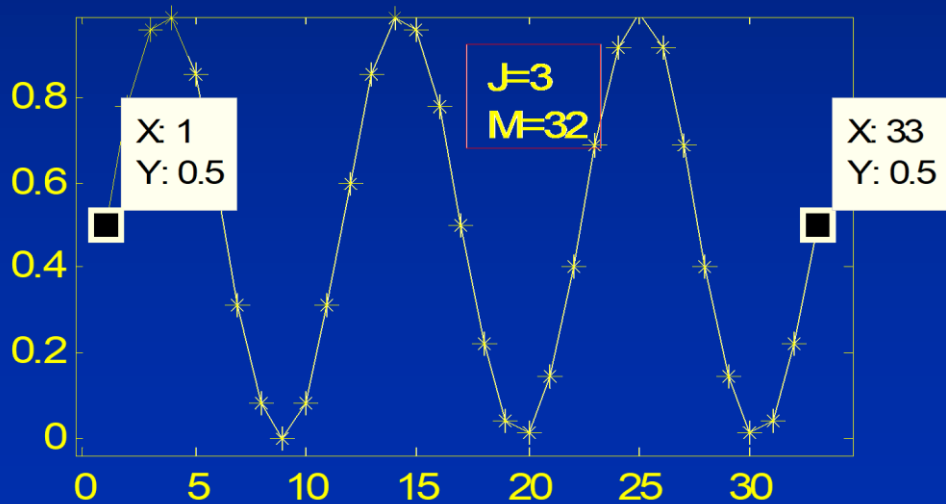
Time domain

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Integer # of input cycles (J) sampled

$$Y[1] = Y[M+1]$$



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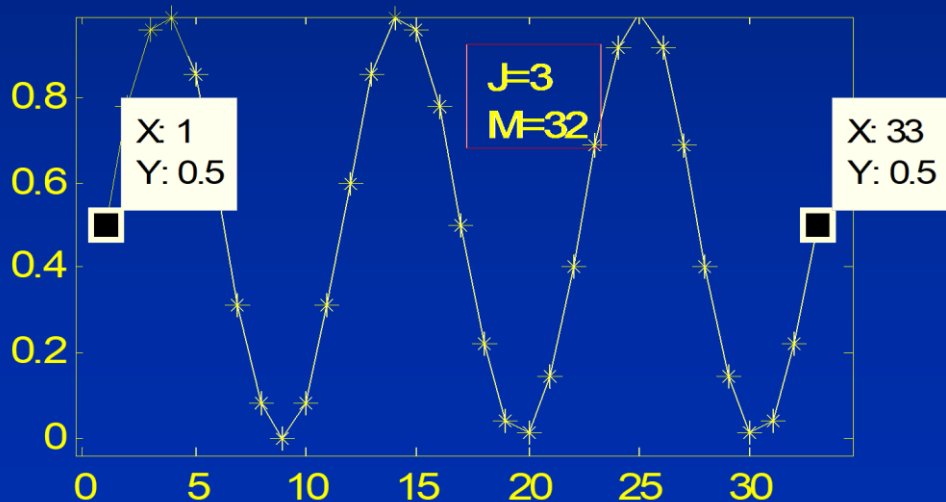
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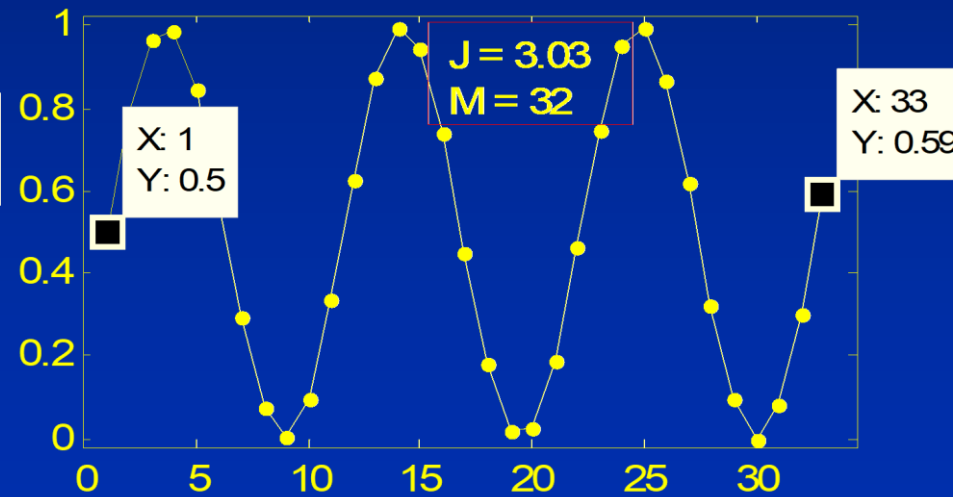
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Non-coherent

Non-integer # of input cycles (J)

$$Y[1] \neq Y[M+1]$$



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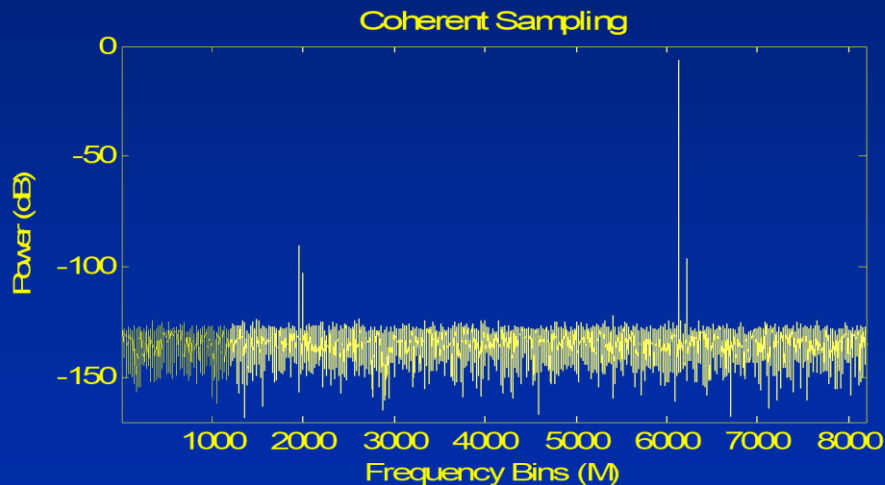
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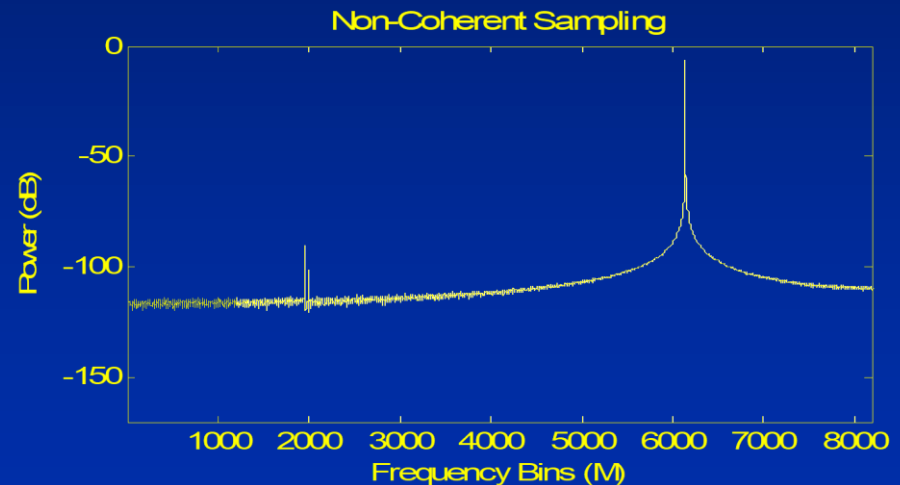
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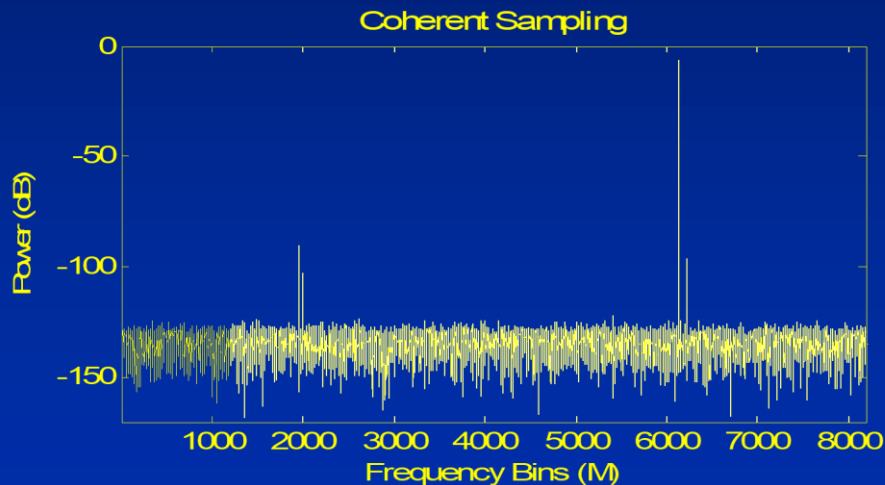
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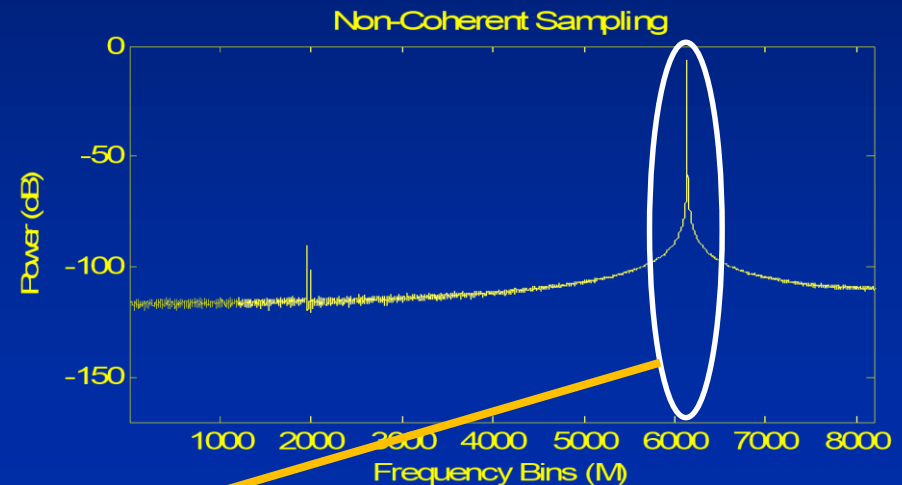
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Severe leakage in the spectrum → Inaccurate results

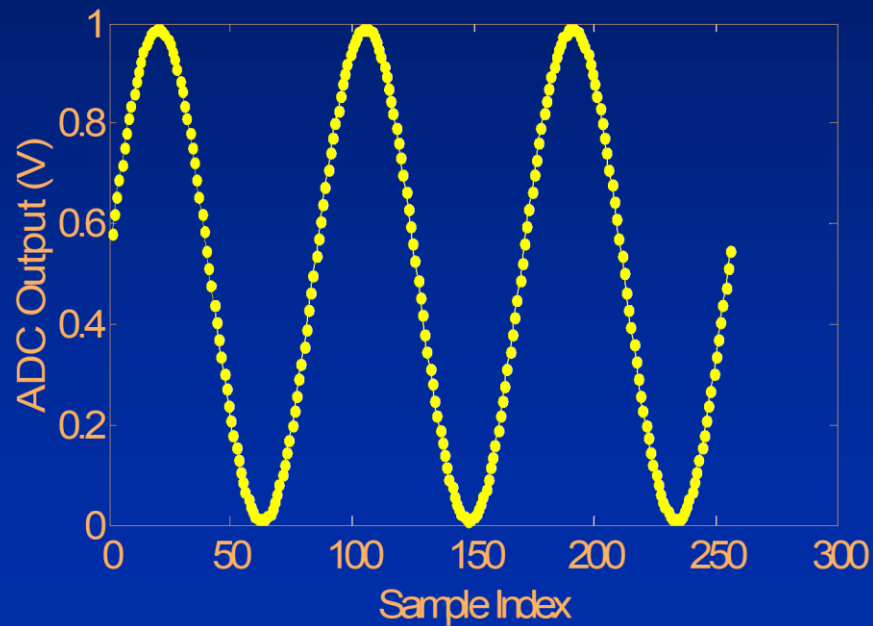
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Input Amplitude

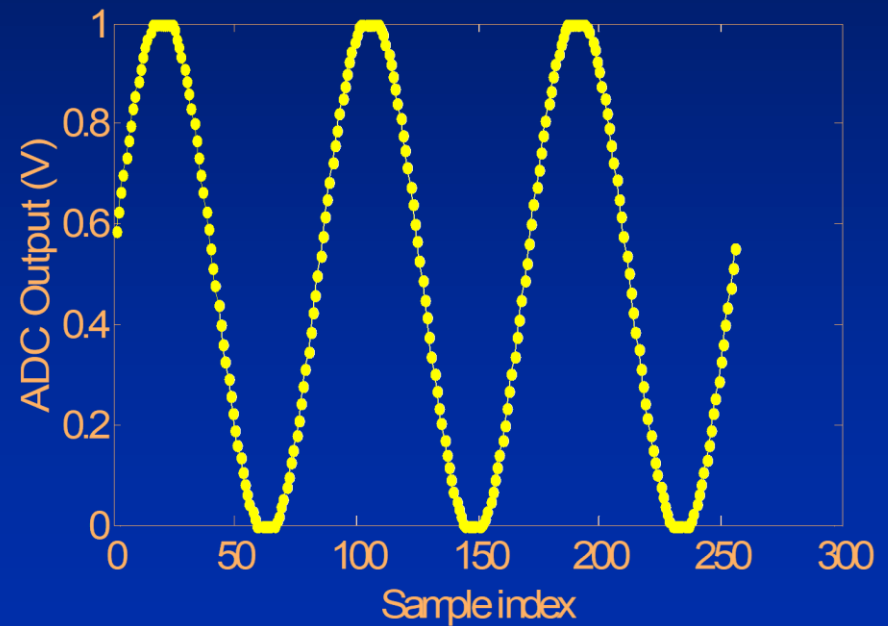
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Time domain

In-range



Over-range



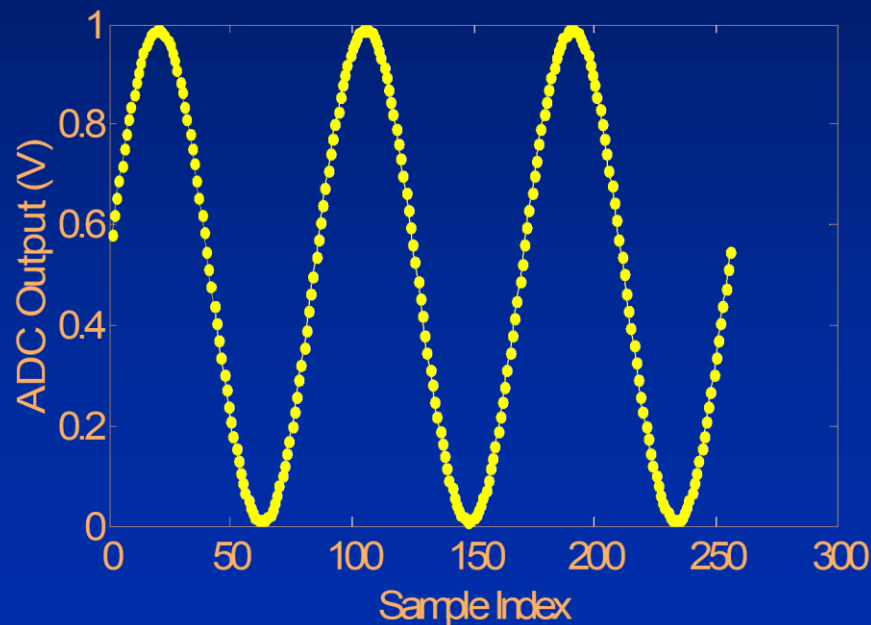
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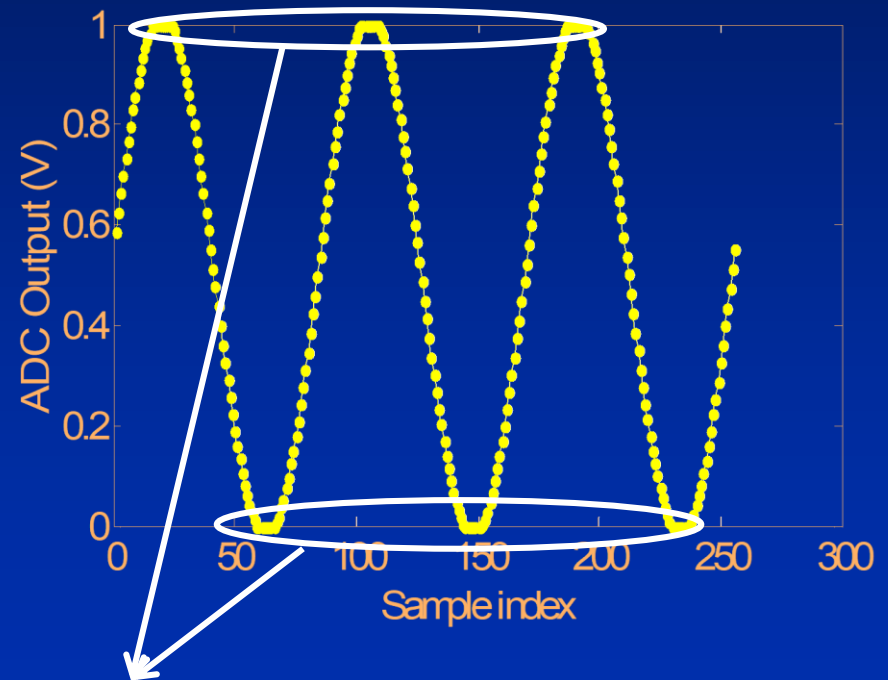
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Over-range input → Clipped ADC output

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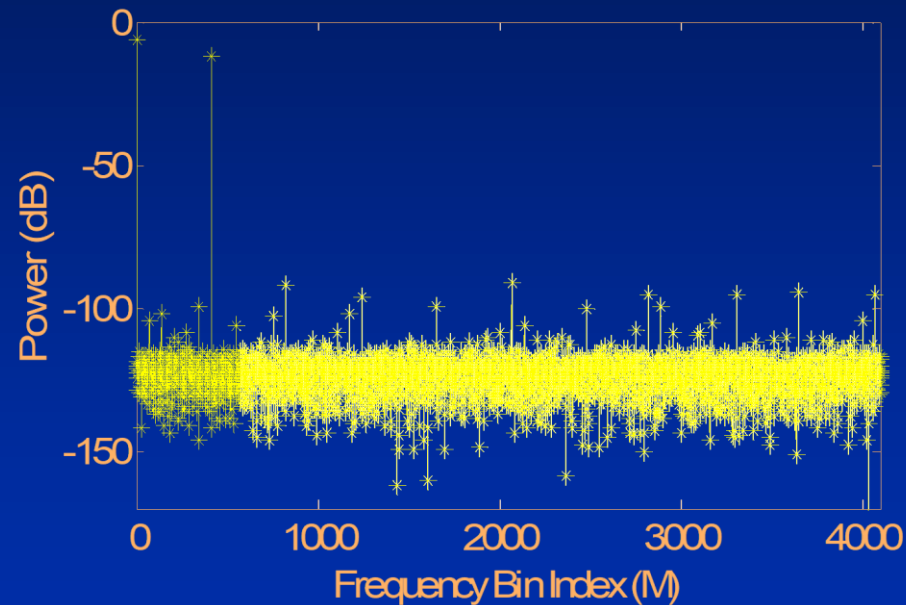
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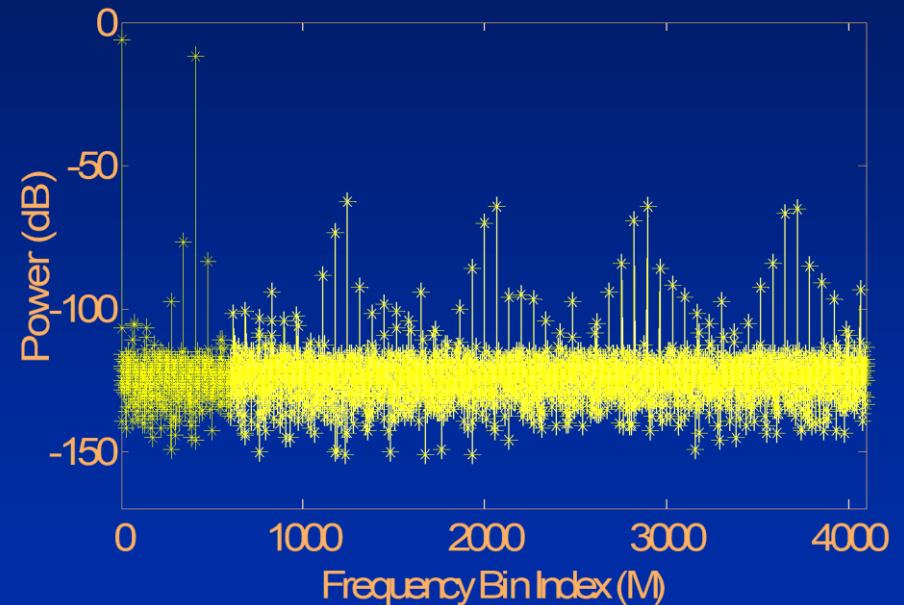
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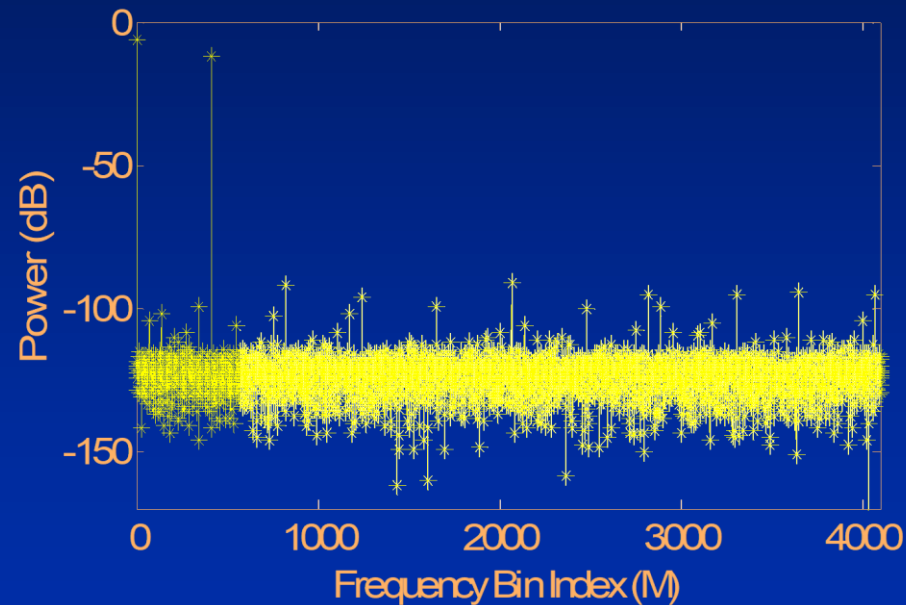
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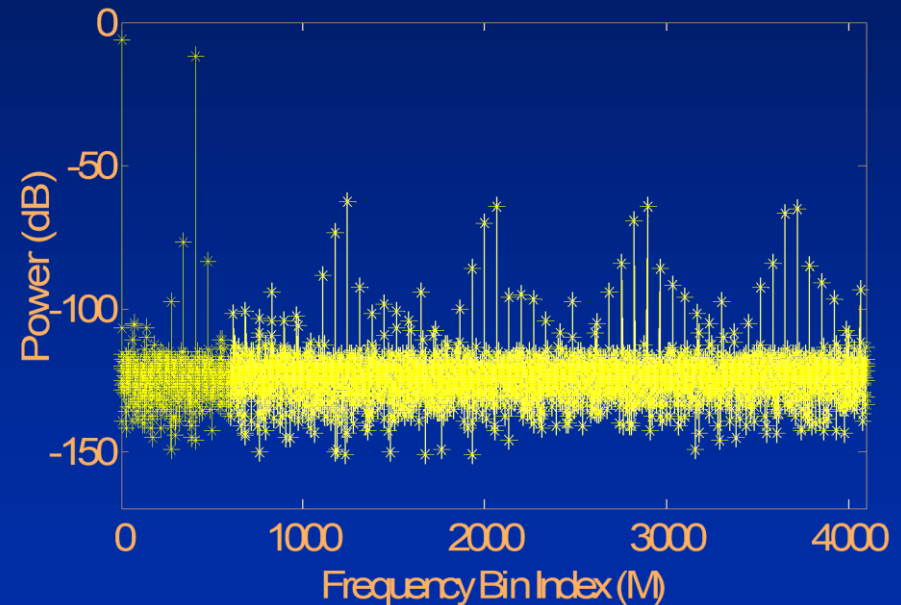
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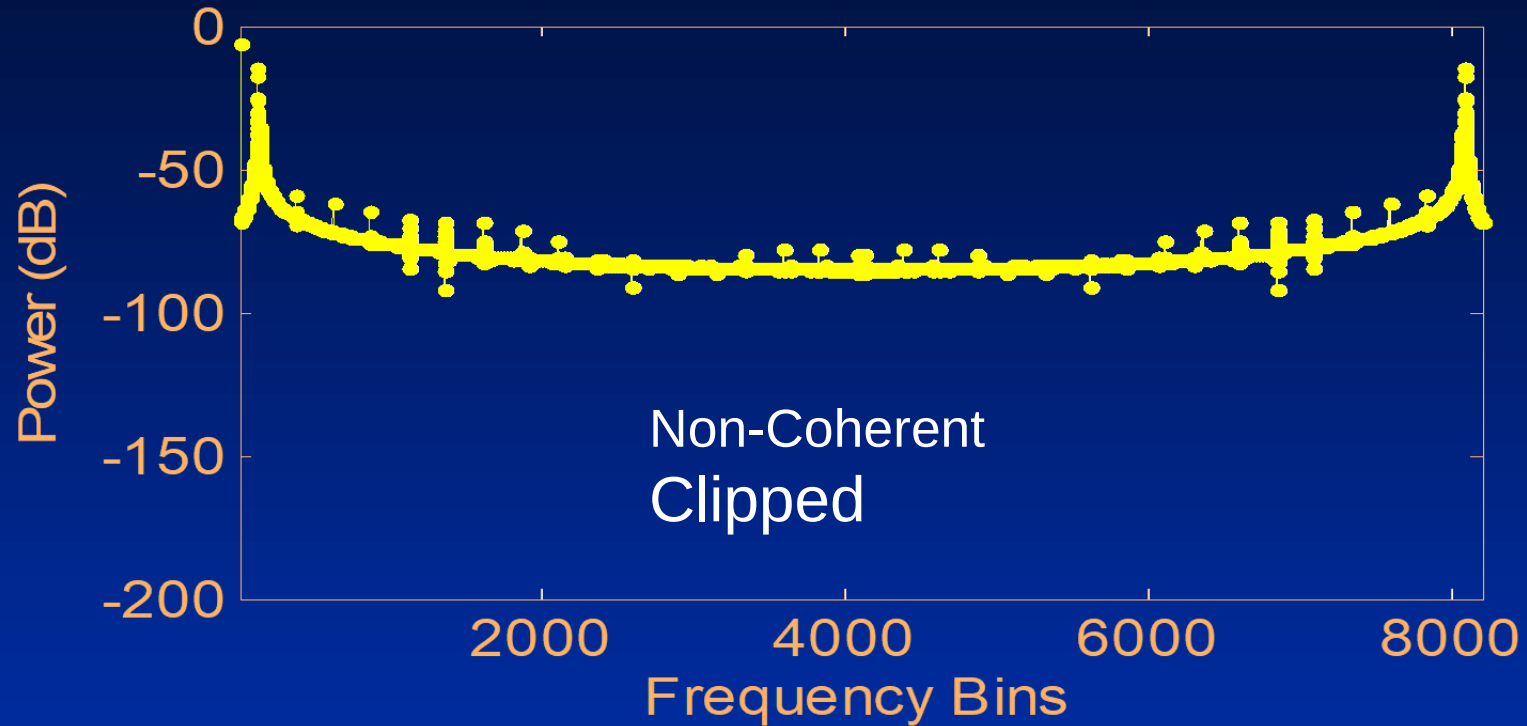
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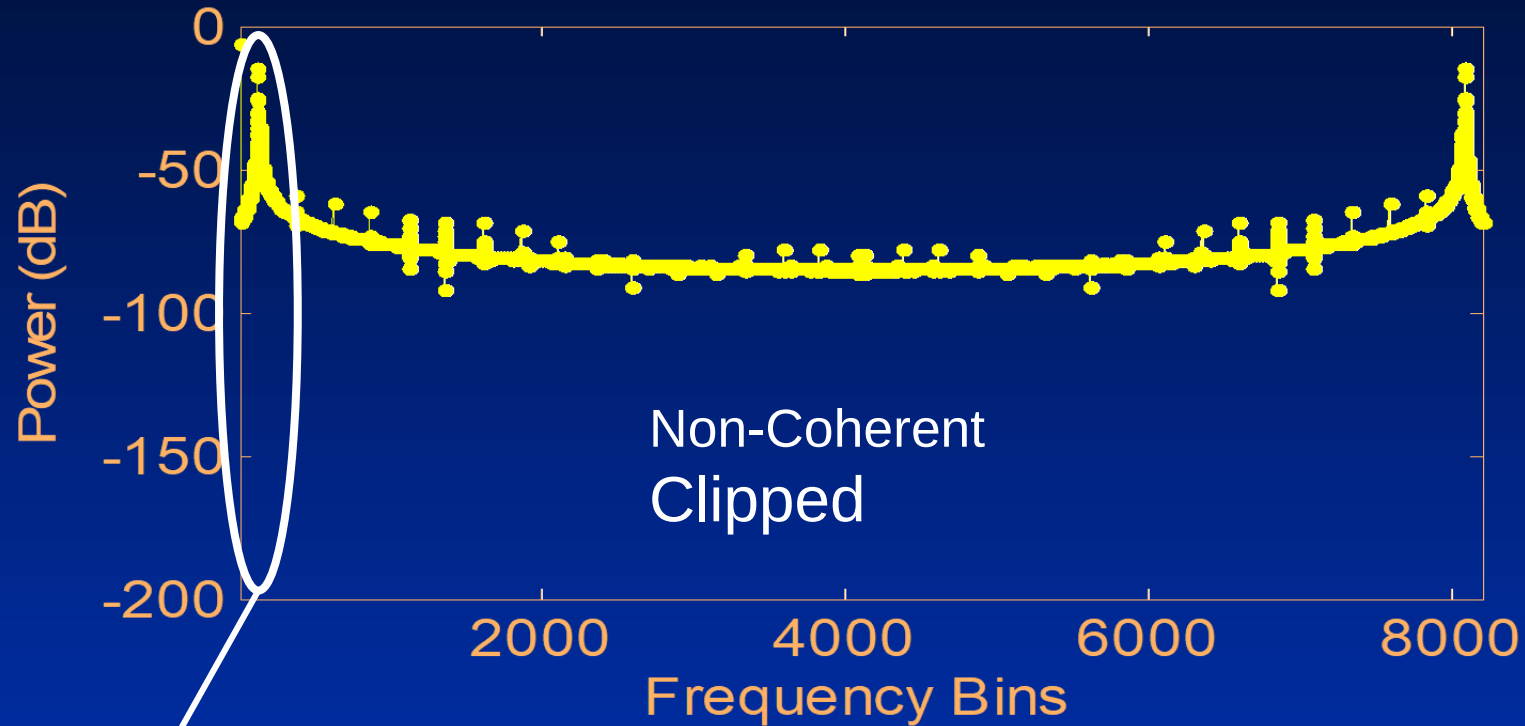
Increase in distortion power → Inaccurate results

Effect of clipping & non-coherency

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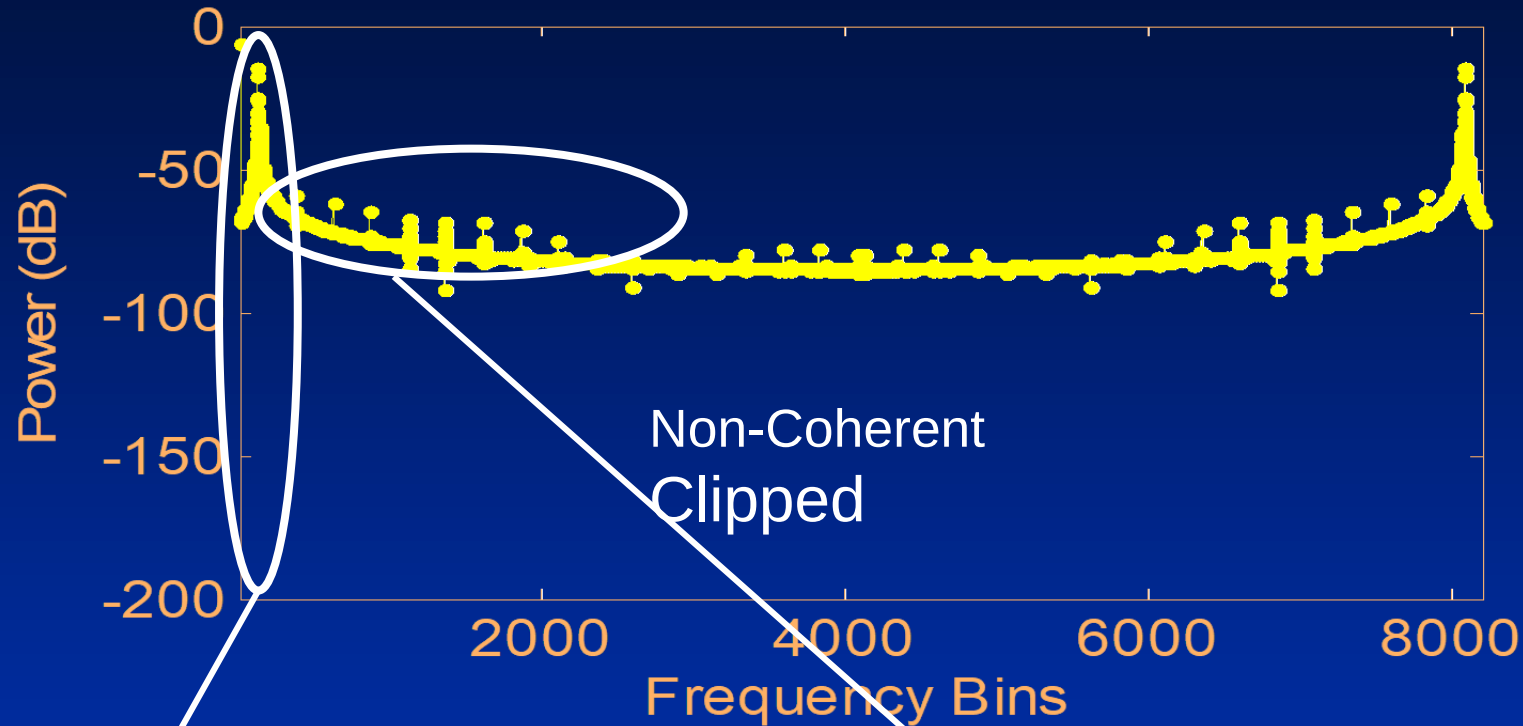


Effect of clipping & non-coherency



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Leakage ← Non-coherent
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Higher
Harmonics ← Clipping

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- Proposed method (FERARI)

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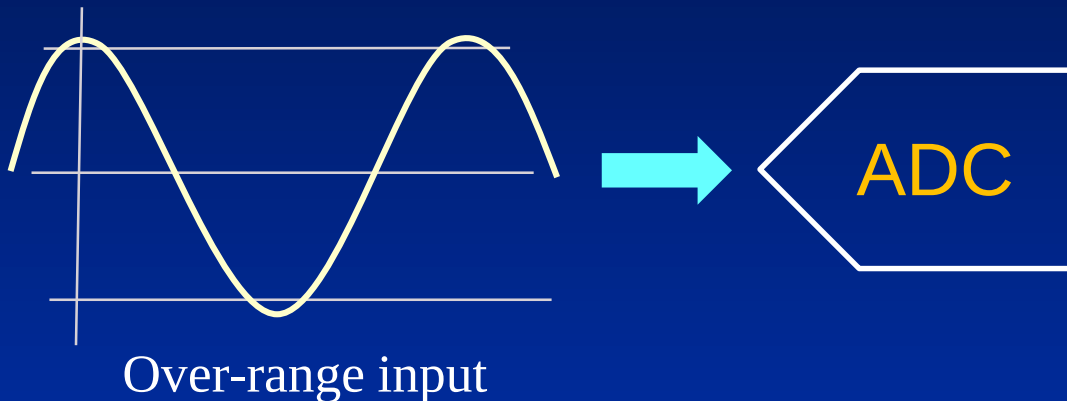
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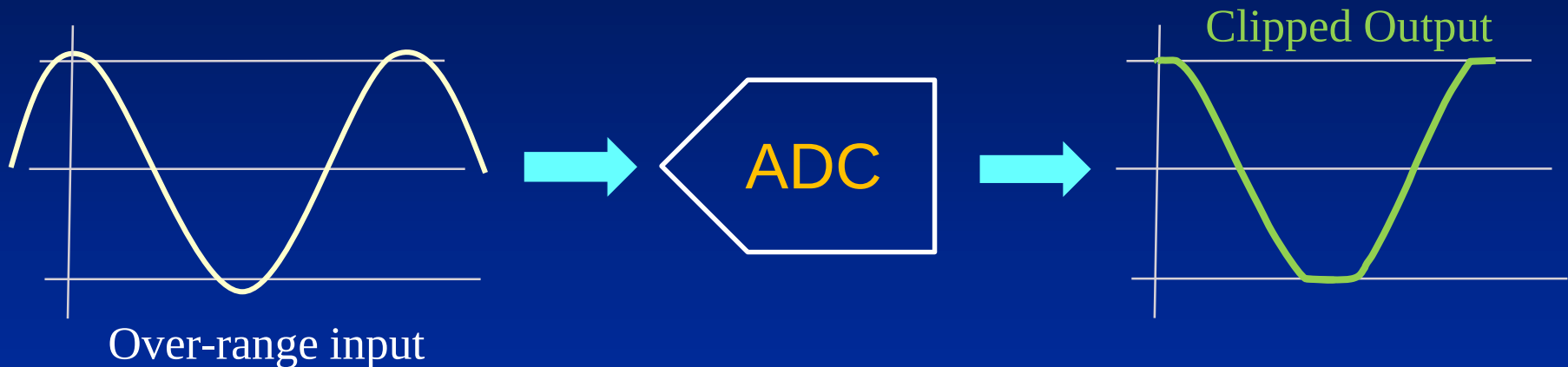
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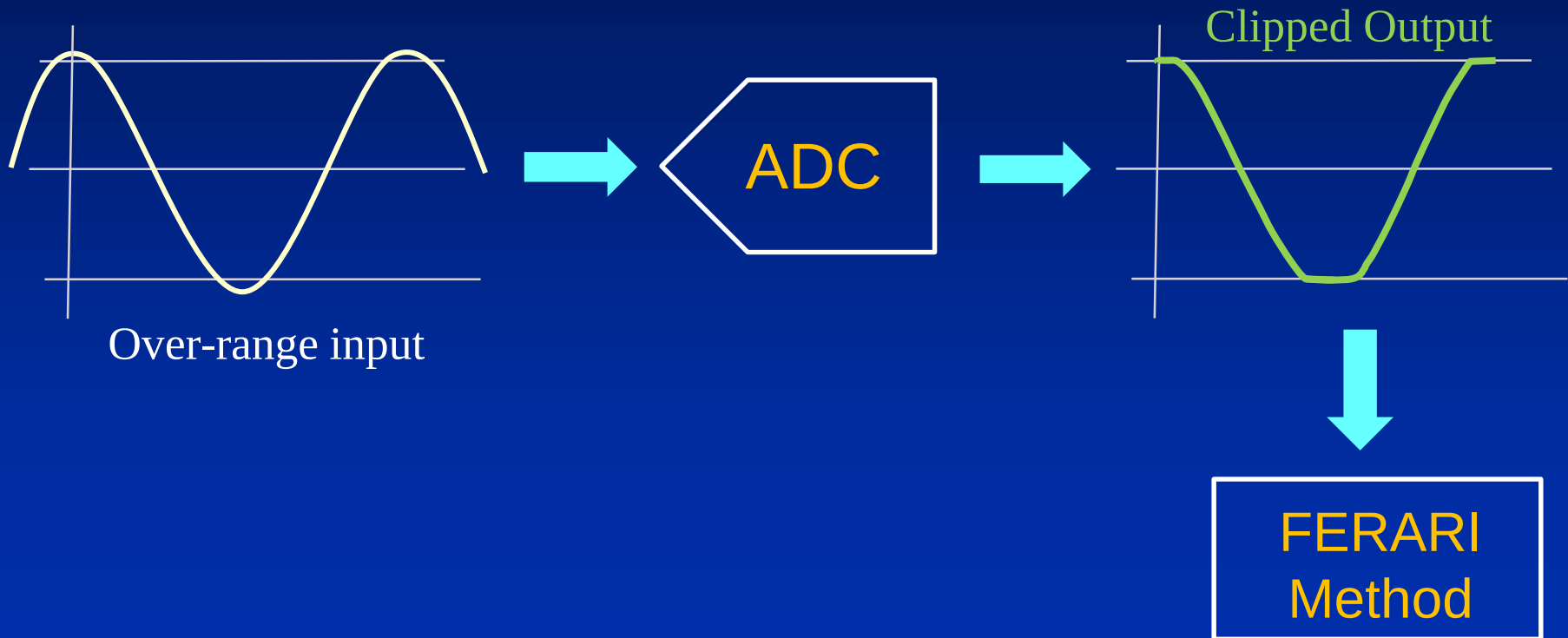
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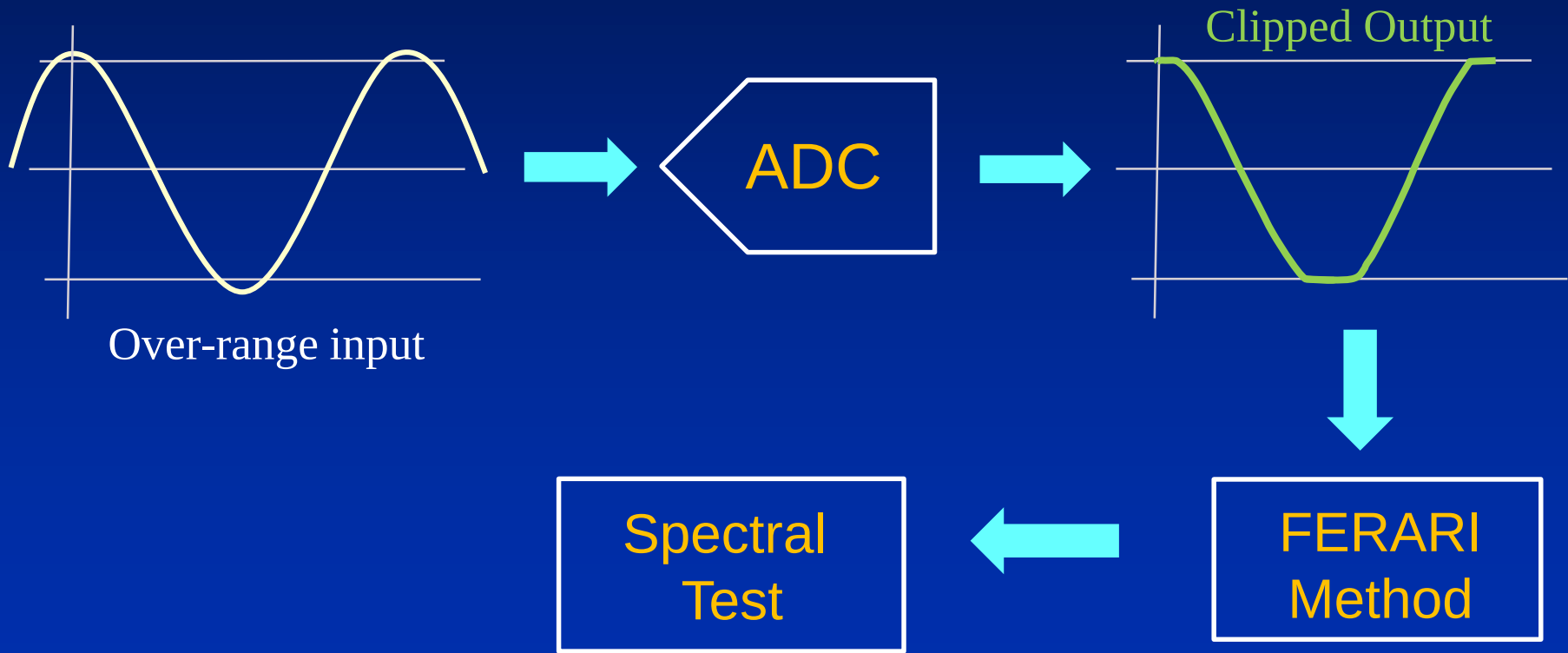
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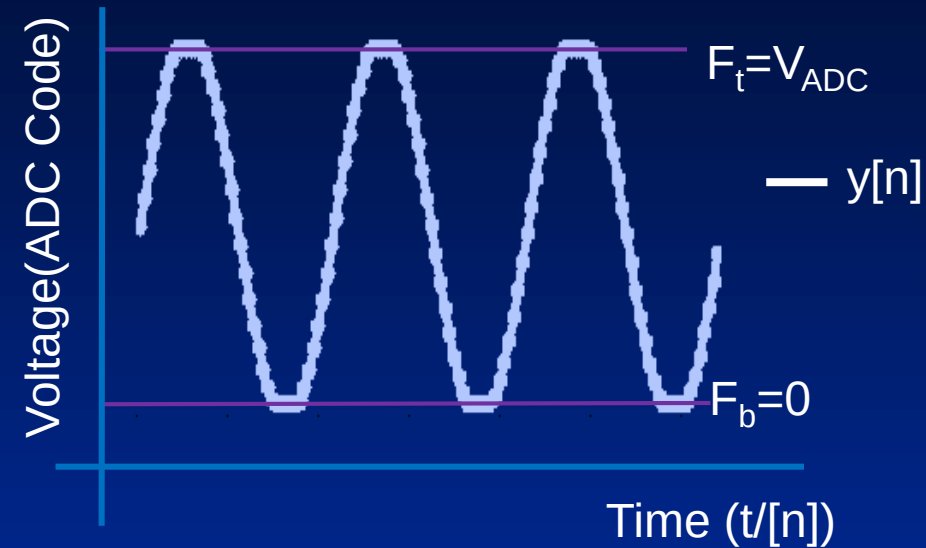
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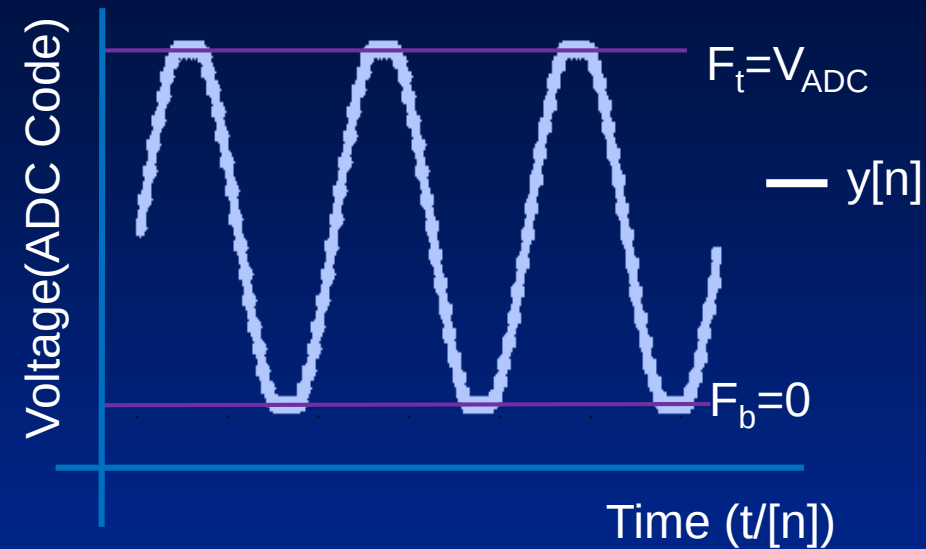
→ New fundamental estimation method is proposed

FERARI (Fundamental Estimation)

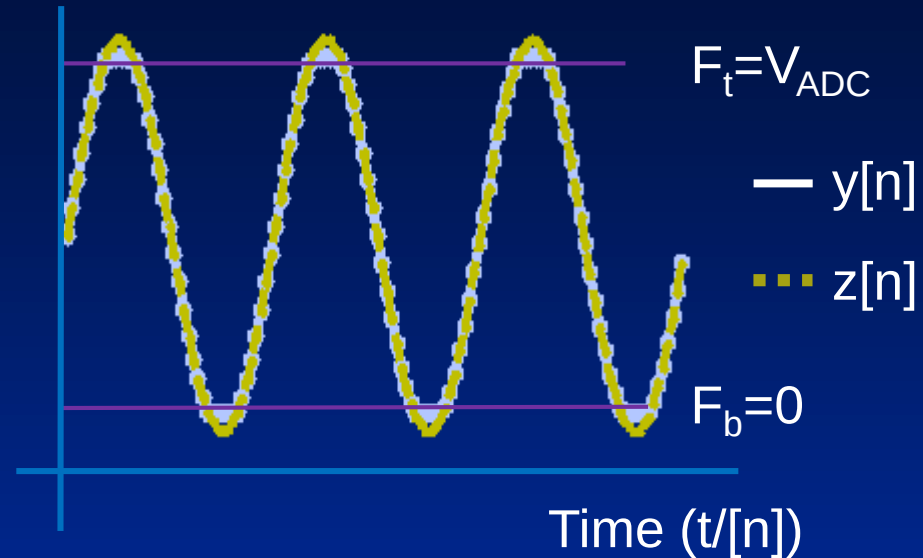


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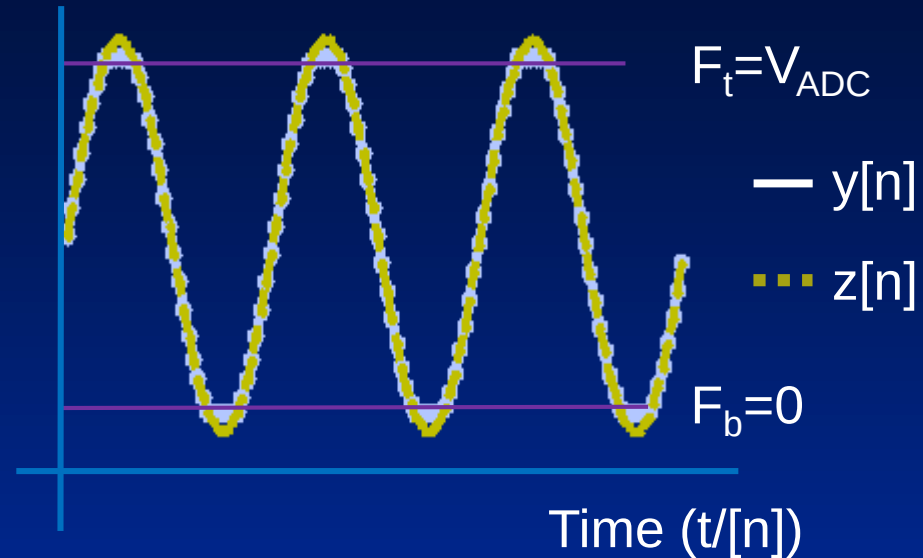
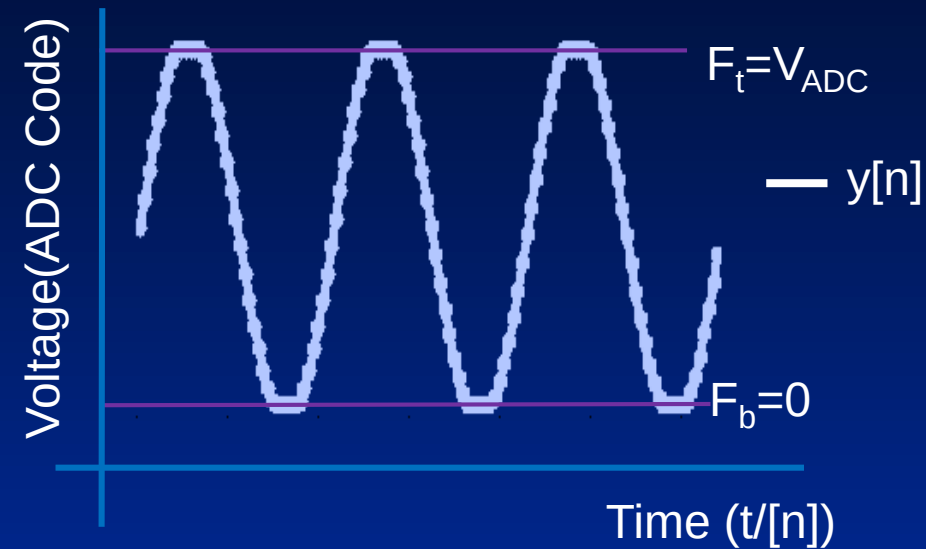


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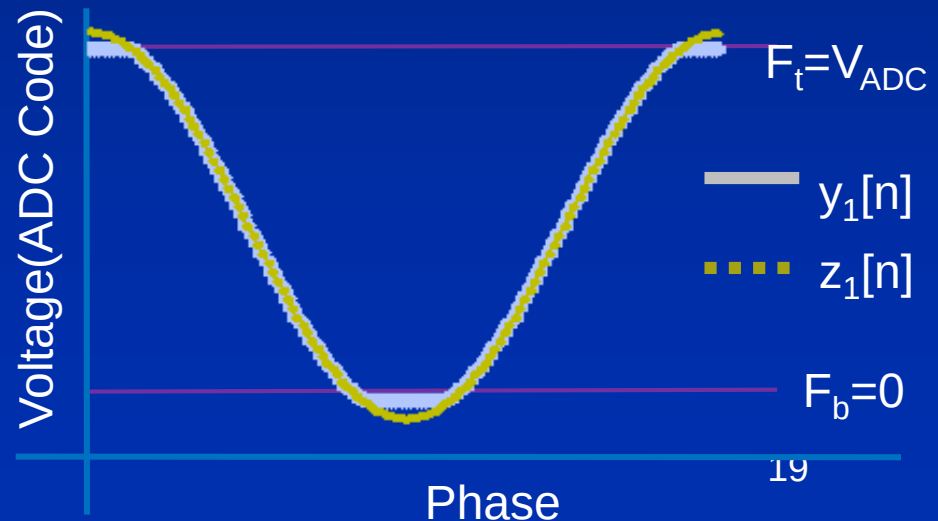
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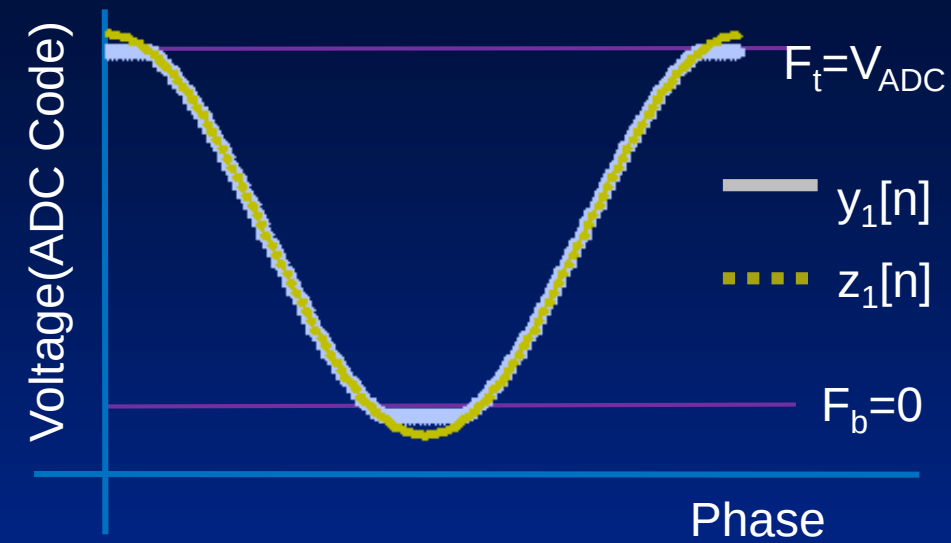
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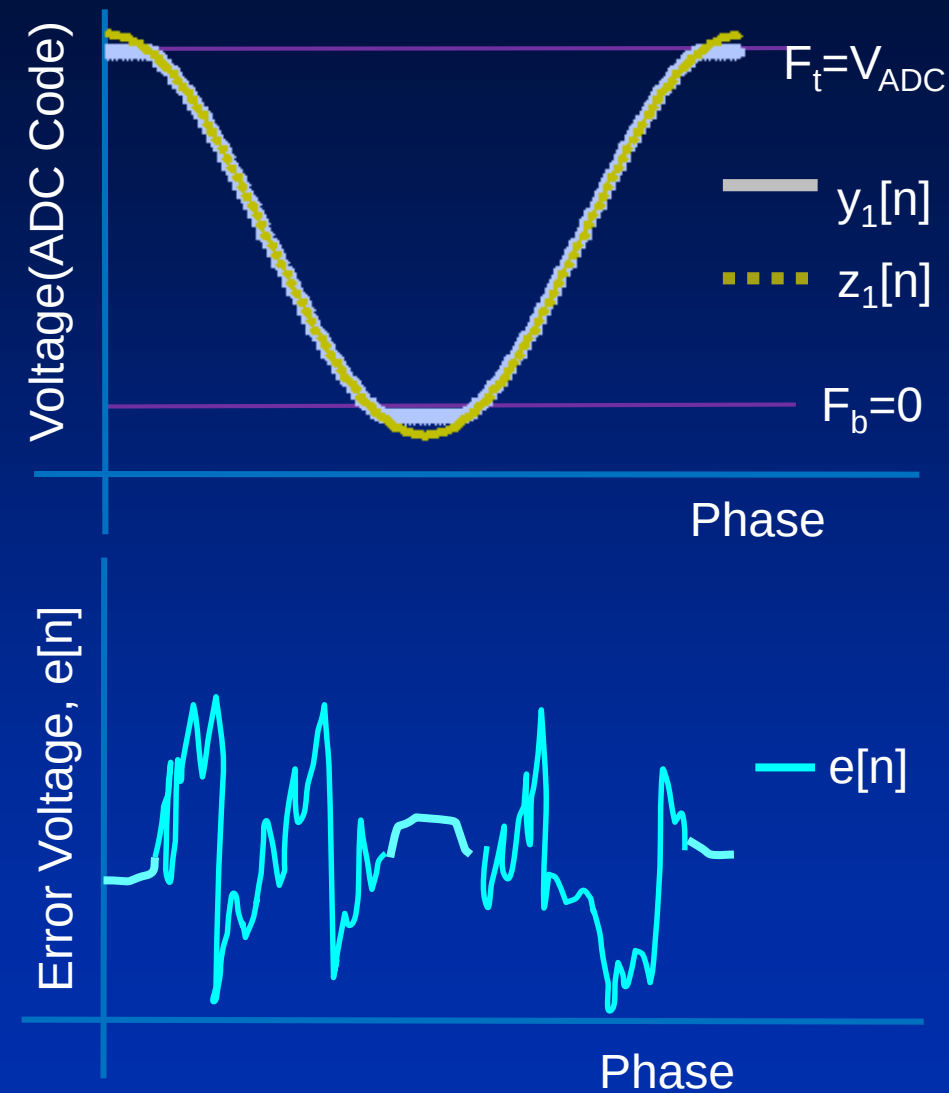
Fold $y[n]$ and $z[n]$ to one cycle



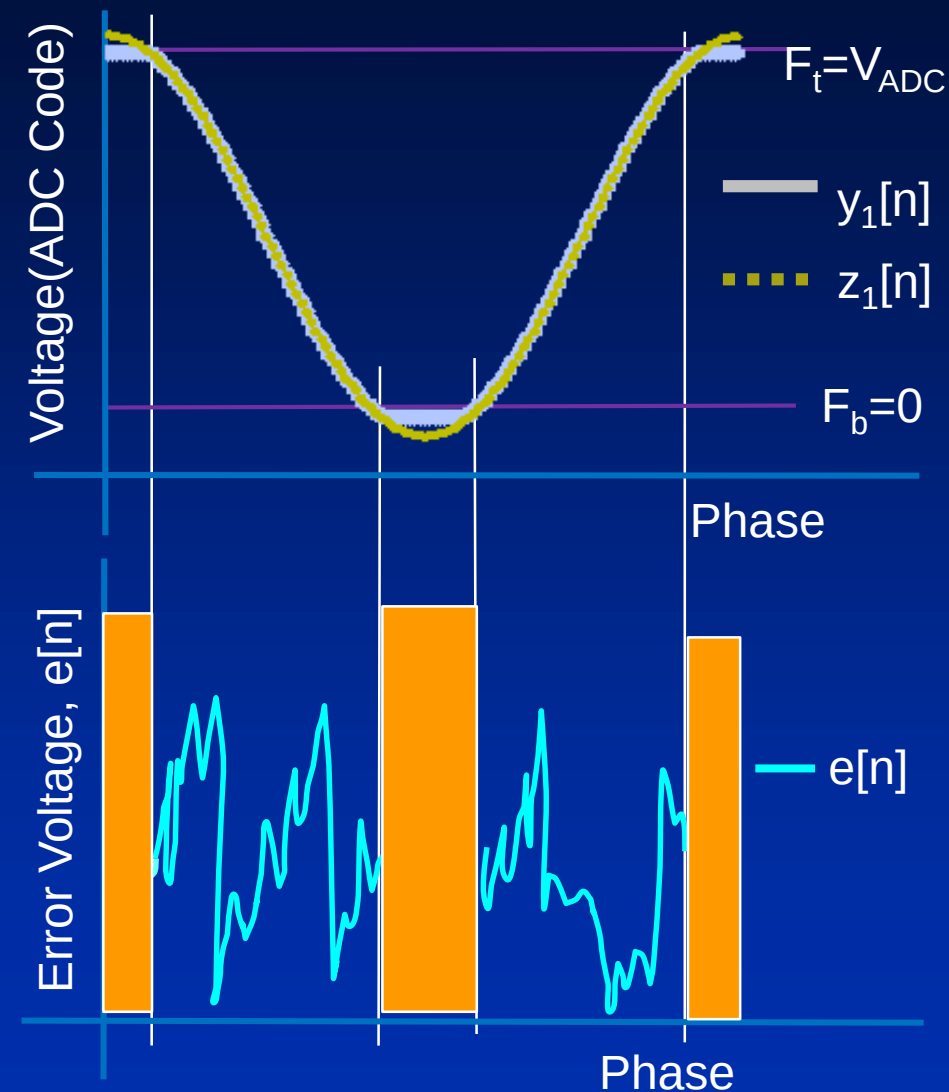
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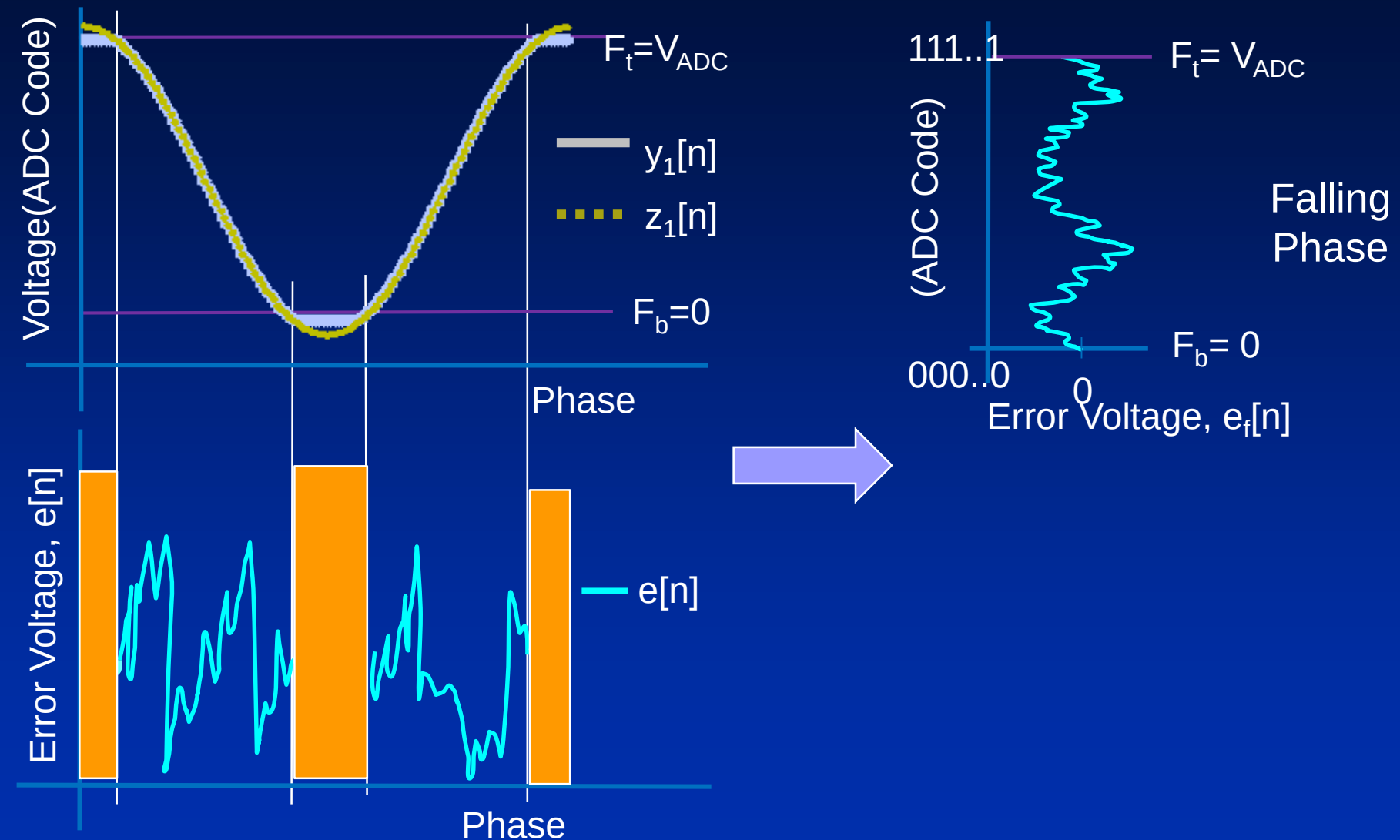


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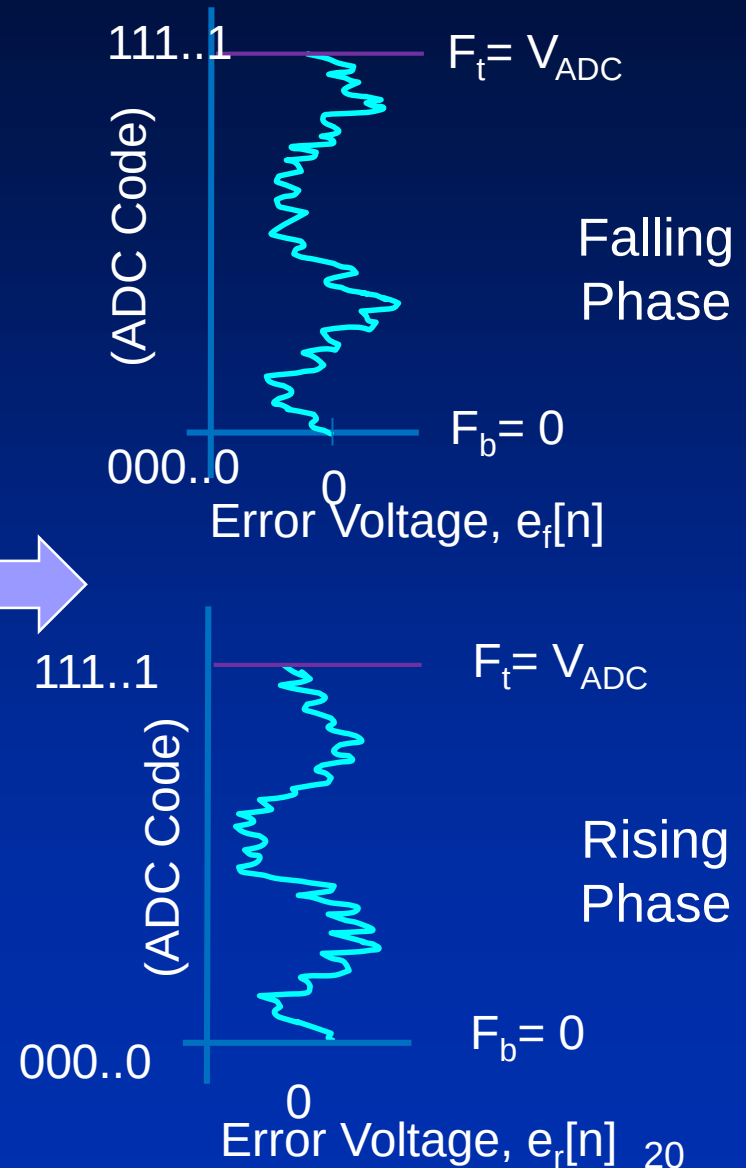
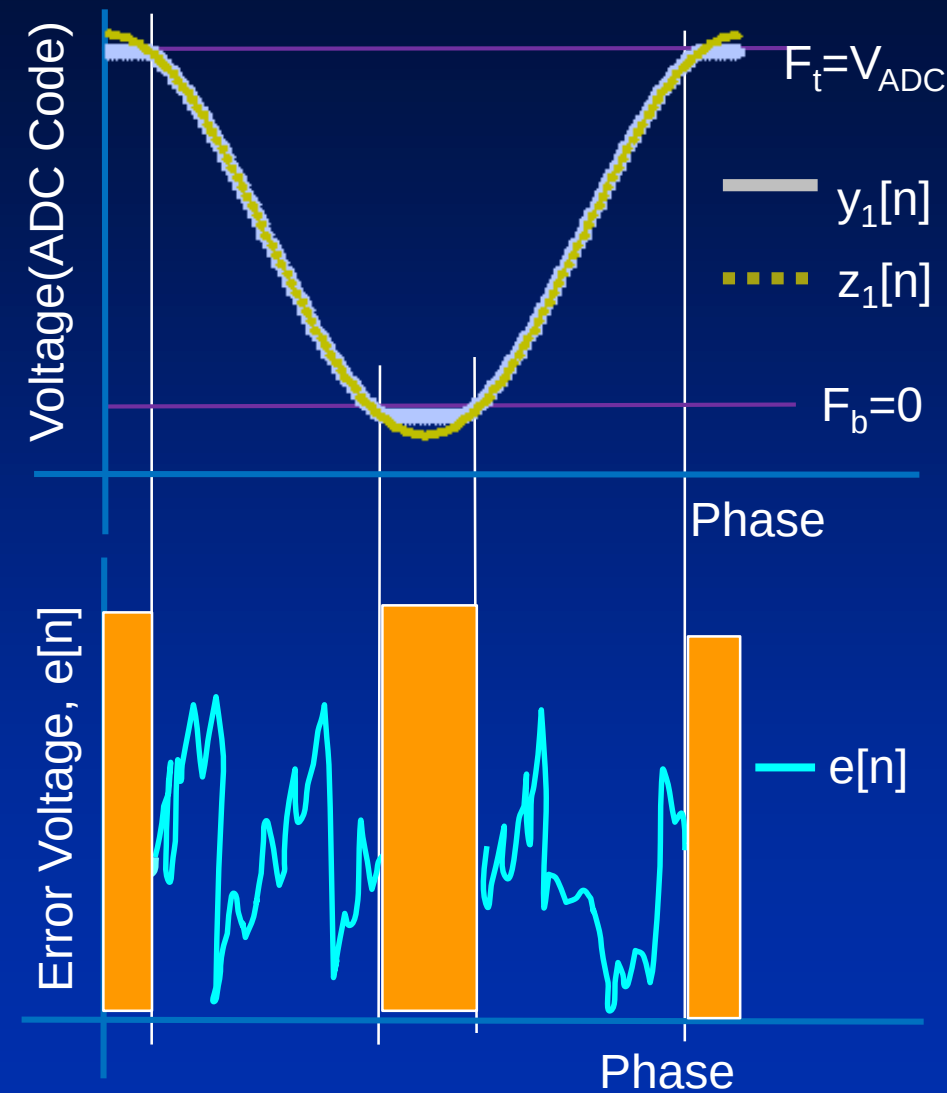
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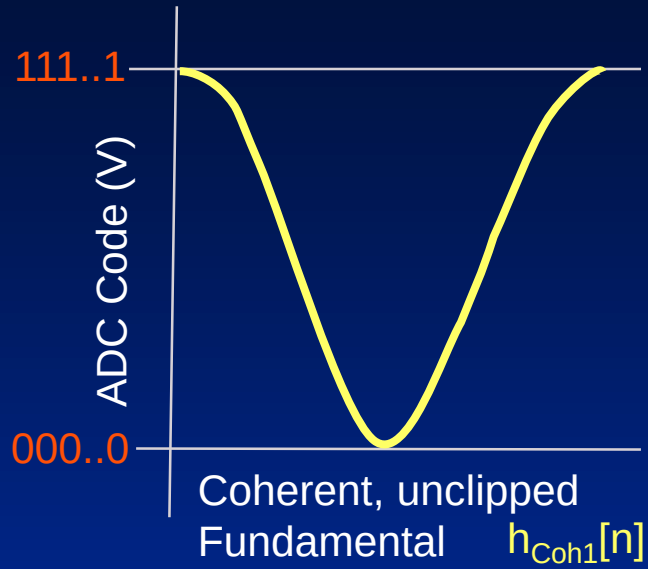
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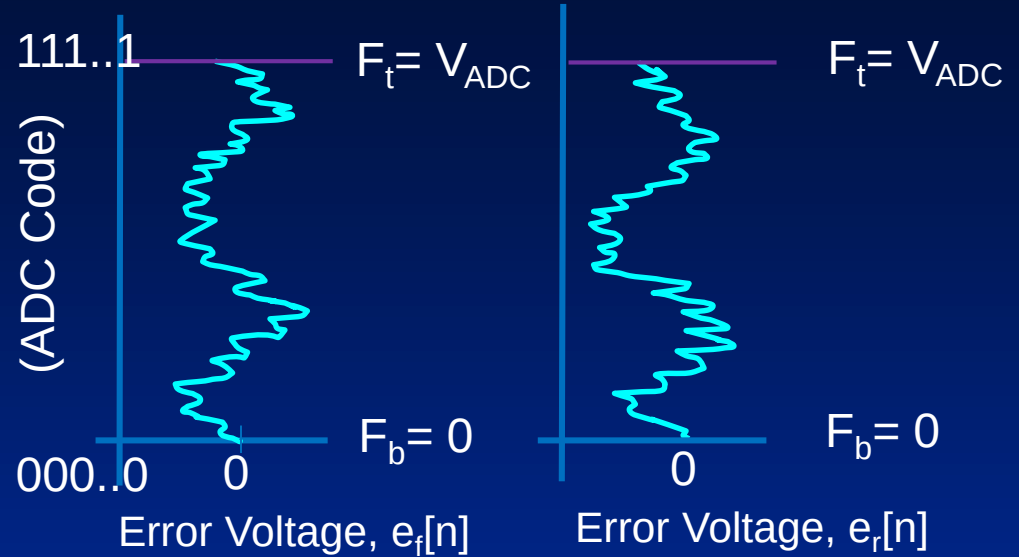
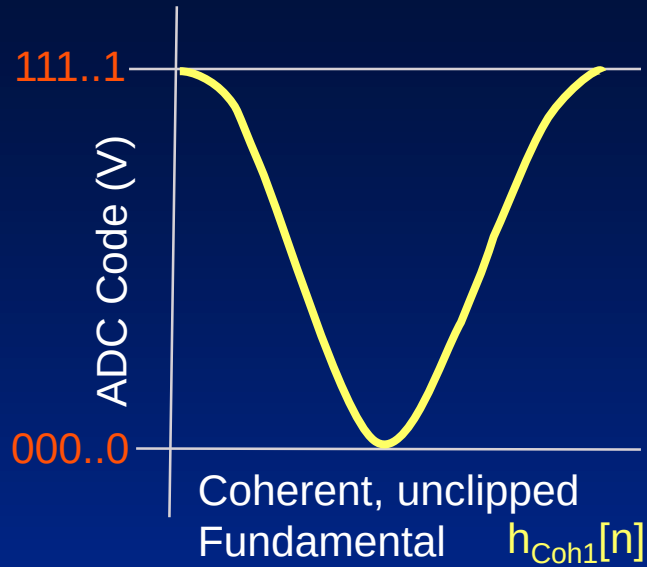
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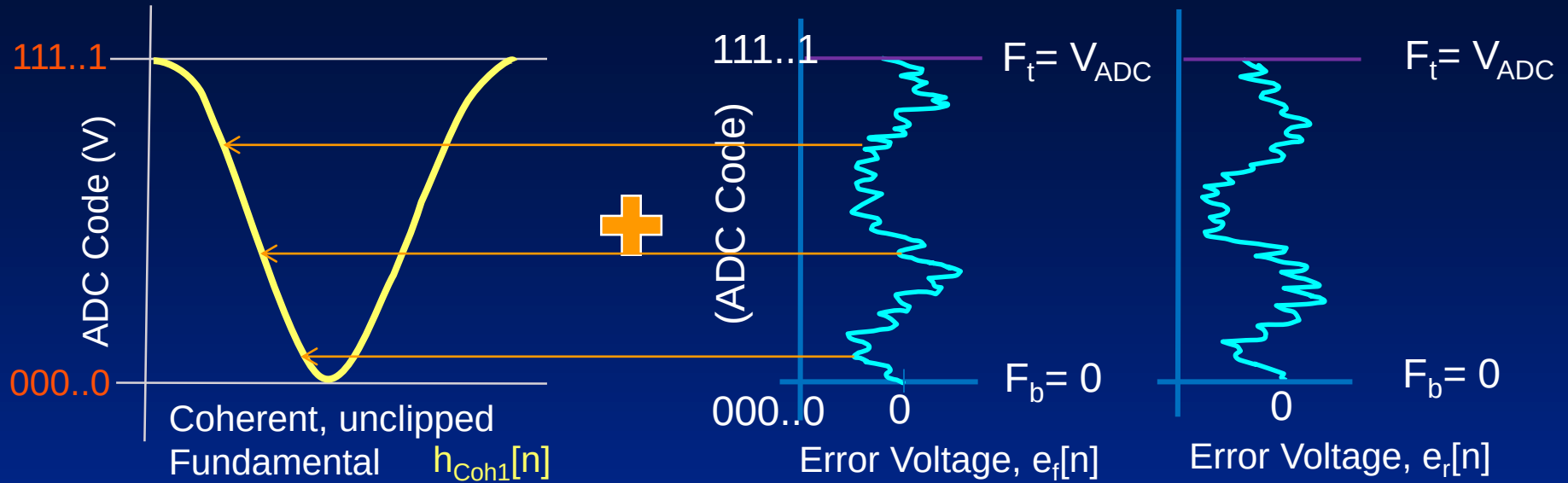
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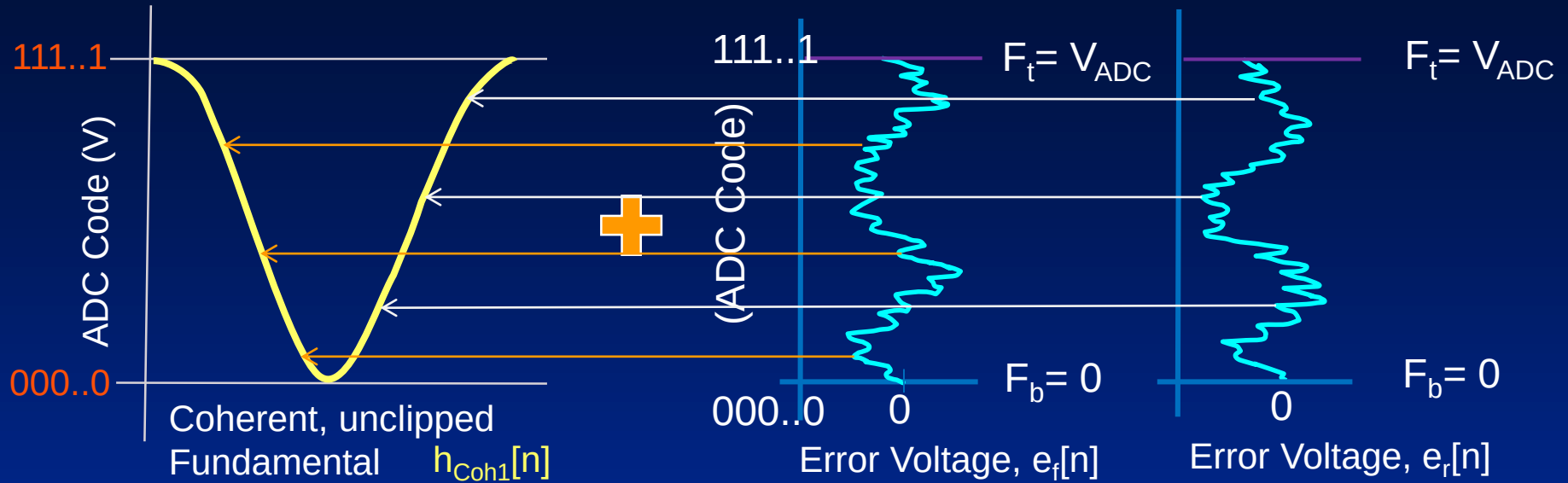
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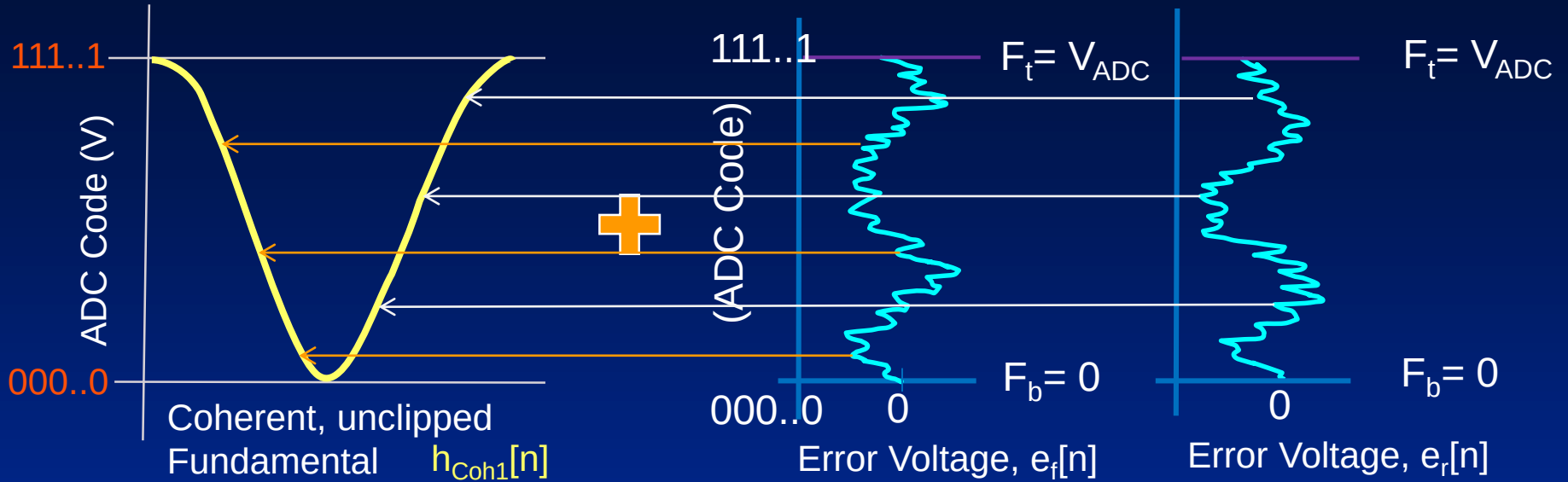
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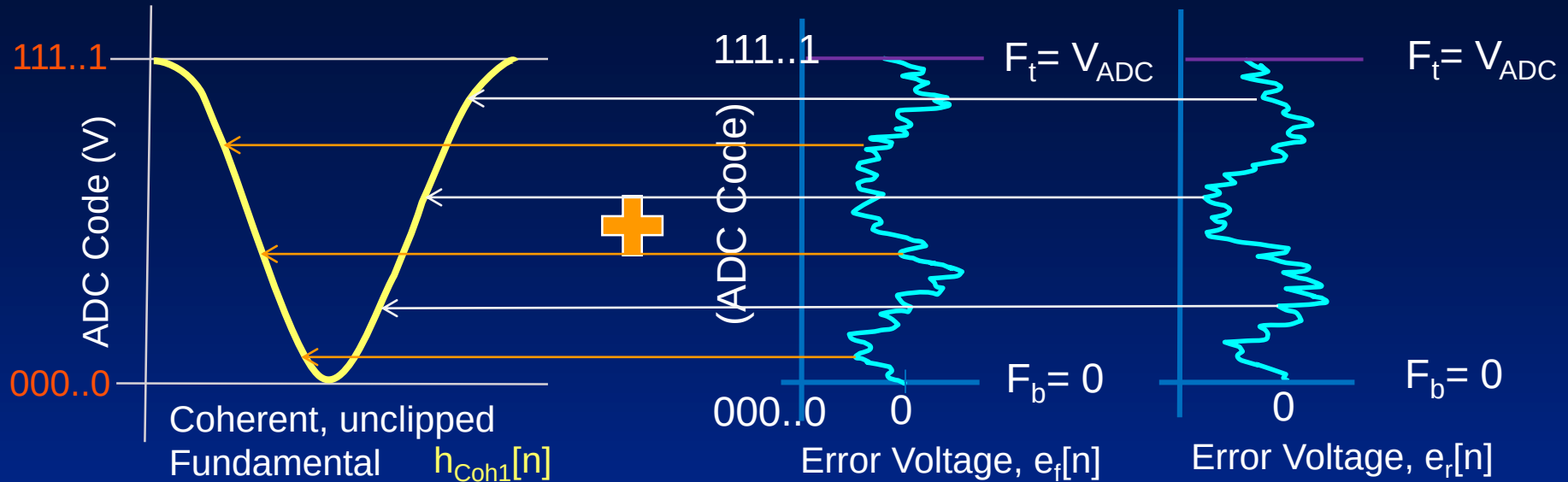


FERARI (Residue Interpolation)



$$f_1[n] = h_{Coh1}[n] + e_{interp1}[n]$$

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Unfold f_1 and perform DFT for spectral test

Fundamental Estimation (A , V_{os})

$$y[n] = V_{os} + A \cos\left(\frac{2\pi J}{M}n + \phi\right) + \sum_{h=2}^H A_h \cos\left(\frac{2\pi hJ}{M}n + \phi_h\right) + w[n] \quad \text{if } 0 < x[n] < V_{ADC}$$

$$J = J_{int} + \delta$$

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Estimate V_{OS} & A (from time domain data)

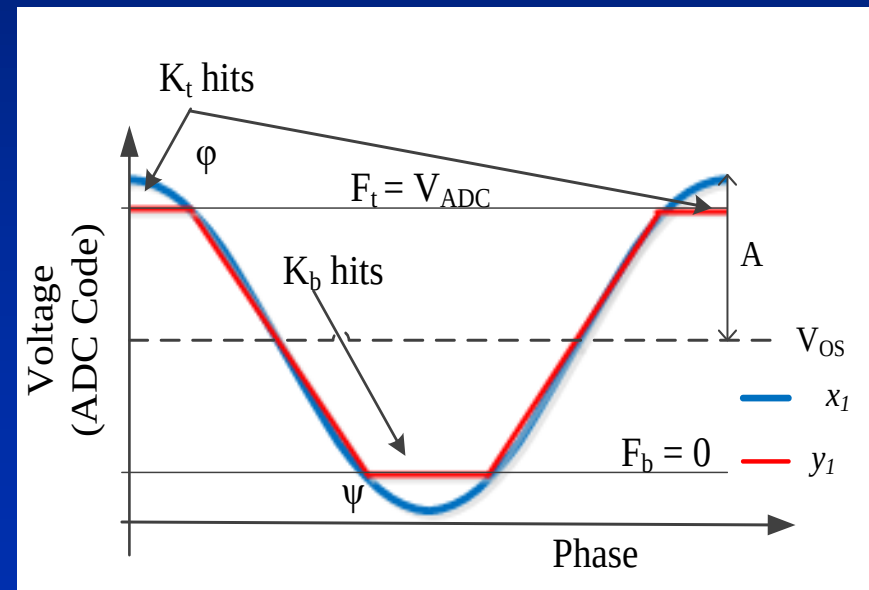
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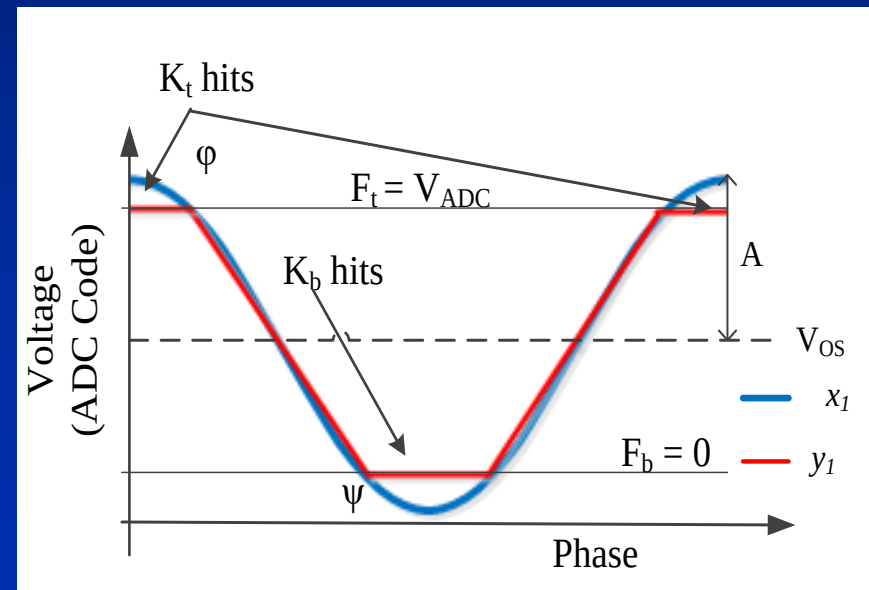
$$J = J_{\text{int}} + \delta$$

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$$A = \frac{F_t - F_b}{\cos\left(\frac{K_t - 1}{M}\pi\right) + \cos\left(\frac{K_b - 1}{M}\pi\right)}$$

$$V_{OS} = \frac{F_t + F_b + A \left\{ \cos\left(\frac{K_b - 1}{M}\pi\right) - \cos\left(\frac{K_t - 1}{M}\pi\right) \right\}}{2}$$



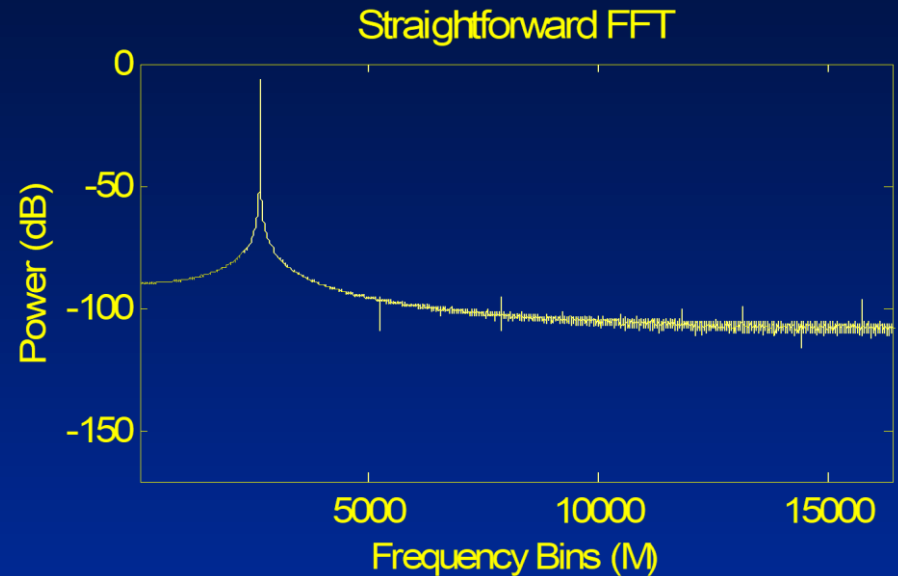
Fundamental Estimation ($\mathbf{J}_{\text{int}}$, δ , ϕ)

Using $y[n]$ and frequency domain data, Y_k

Fundamental Estimation (J_{int} , δ , ϕ)

Using $y[n]$ and frequency domain data, Y_k

$Y_k \rightarrow k^{\text{th}}$ DFT coefficient of $y[n]$

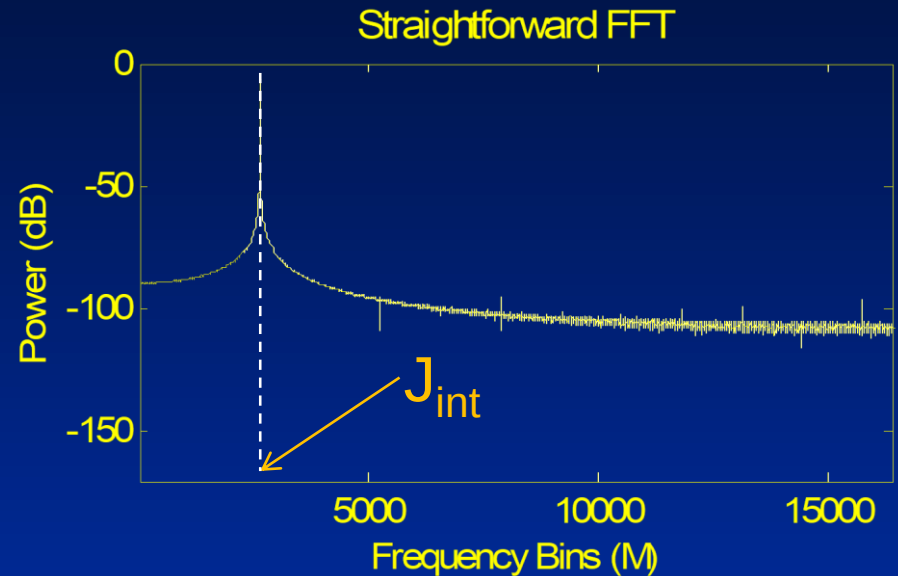


Fundamental Estimation (J_{int} , δ , ϕ)

Using $y[n]$ and frequency domain data, Y_k

$Y_k \rightarrow k^{\text{th}}$ DFT coefficient of $y[n]$

$$J_{\text{int}} = \arg \max_{1 \leq k \leq M/2} |Y_k|$$

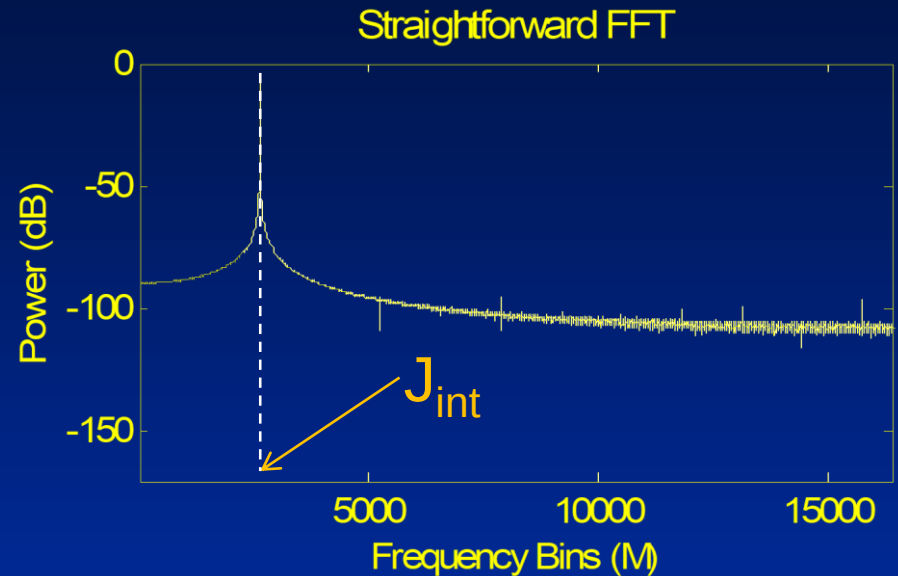


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Initial estimates of δ and ϕ

$$\delta_0 = -\frac{M}{2\pi} \text{imag} \left(\ln \left(\frac{\frac{Y_{J_{\text{int}}}}{Y_{J_{\text{int}}+1}} - \frac{Y_{J_{\text{int}}}}{Y_{J_{\text{int}}-1}}}{\frac{Y_{J_{\text{int}}}}{Y_{J_{\text{int}}+1}} - \frac{Y_{J_{\text{int}}}}{Y_{J_{\text{int}}-1}} + e^{j\frac{2\pi}{M}} - e^{-j\frac{2\pi}{M}}} \right) \right)$$

$$\phi_0 = -\text{imag} \left(\ln \left(\frac{2MY_{J_{\text{int}}}}{\hat{A}} \frac{1 - e^{j\frac{2\pi\delta_0}{M}}}{1 - e^{j2\pi\delta_0}} \right) \right)$$

Fundamental Estimation

$$y[n] = V_{os} + A * \sin\left(\frac{2\pi J}{M} n + \phi\right) + HD + w[n]$$

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To improve accuracy in δ and ϕ

$$\Delta\delta = \delta - \delta_0 \quad \Delta\phi = \phi - \phi_0$$

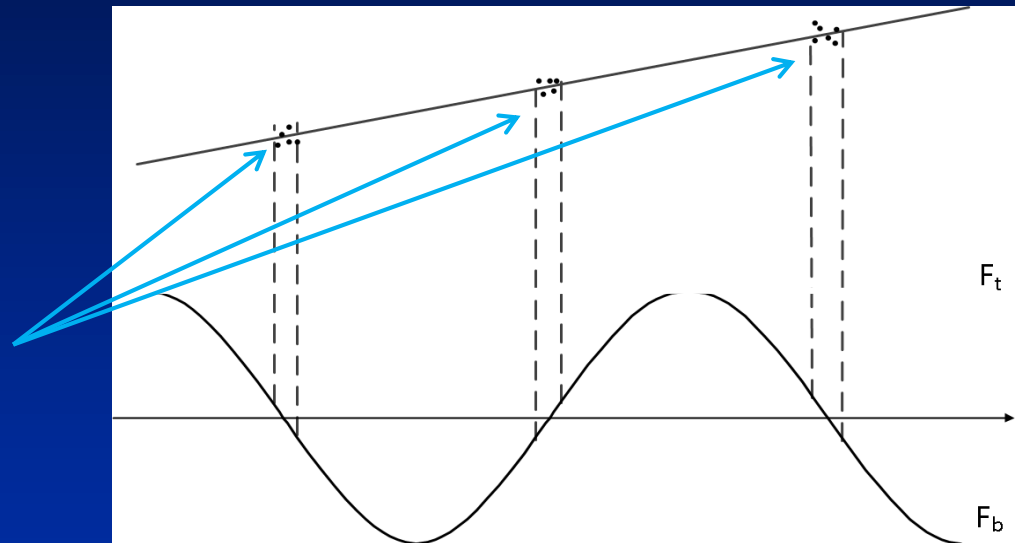
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Estimate $\Delta\delta$ and $\Delta\phi$ using
Least squares on points
close to mid-range codes



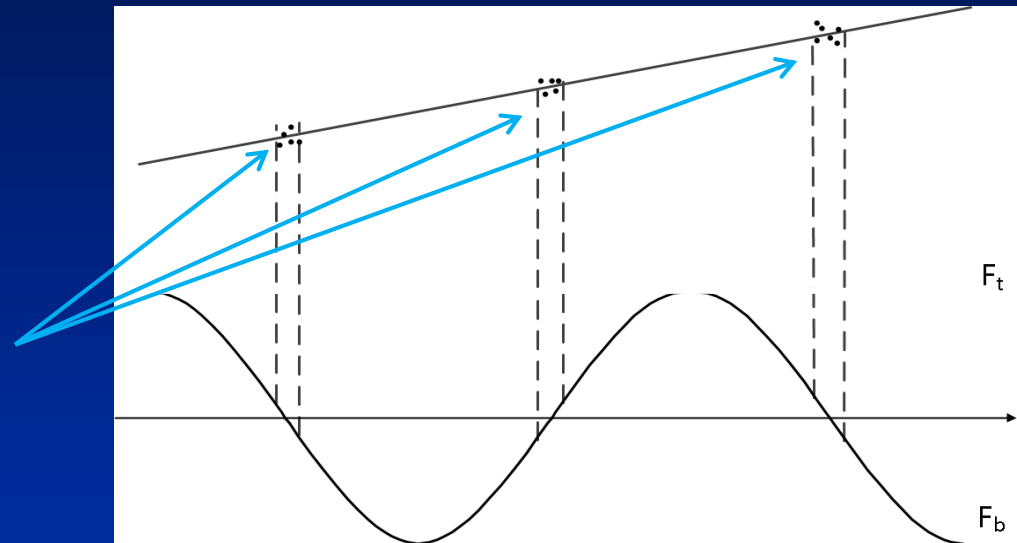
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Estimate $\Delta\delta$ and $\Delta\phi$ using
Least squares on points
close to mid-range codes



$$\frac{2\pi n}{M} \Delta\delta + \Delta\phi = \cos^{-1}\left(\frac{y[n] - V_{os}}{A}\right) - \phi_0 - \frac{2\pi(J_{\text{int}} + \delta_0)n}{M} \rightarrow n \text{ corresponds to mid-code points}$$

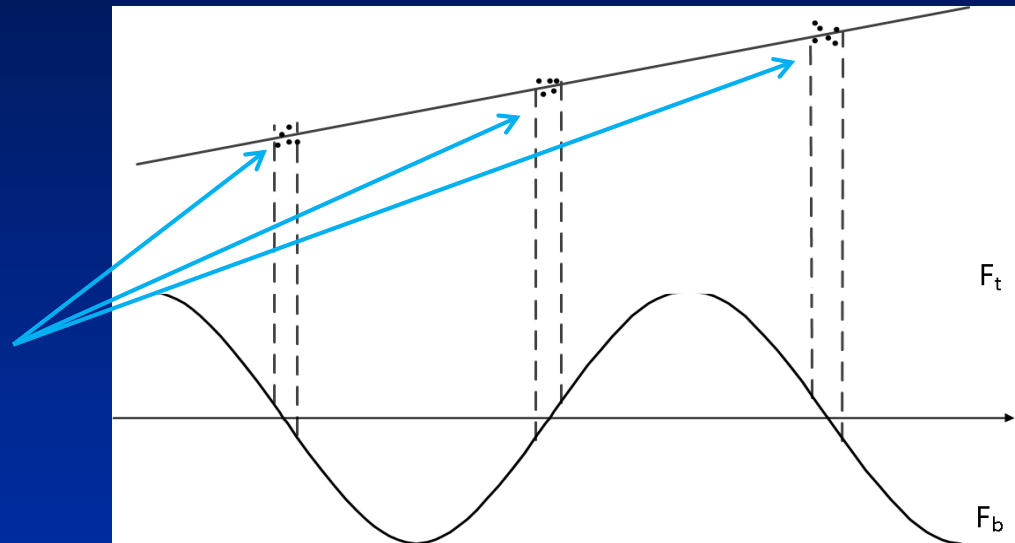
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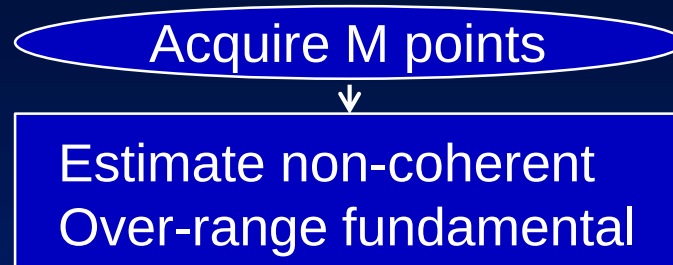
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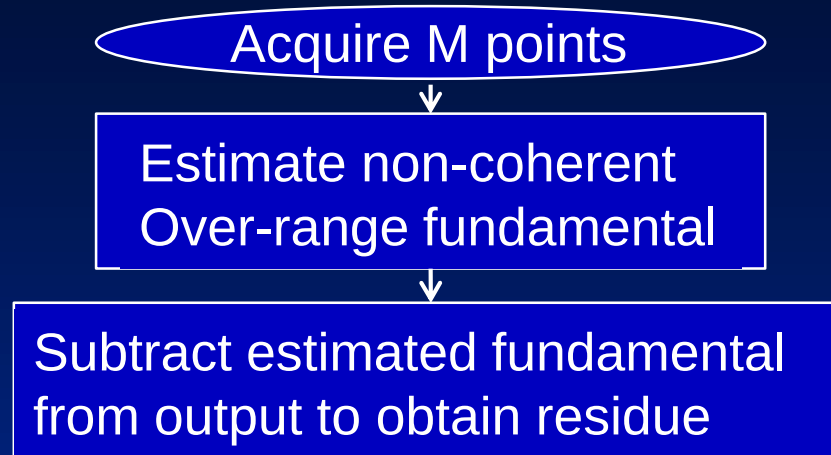
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Fundamental Estimated

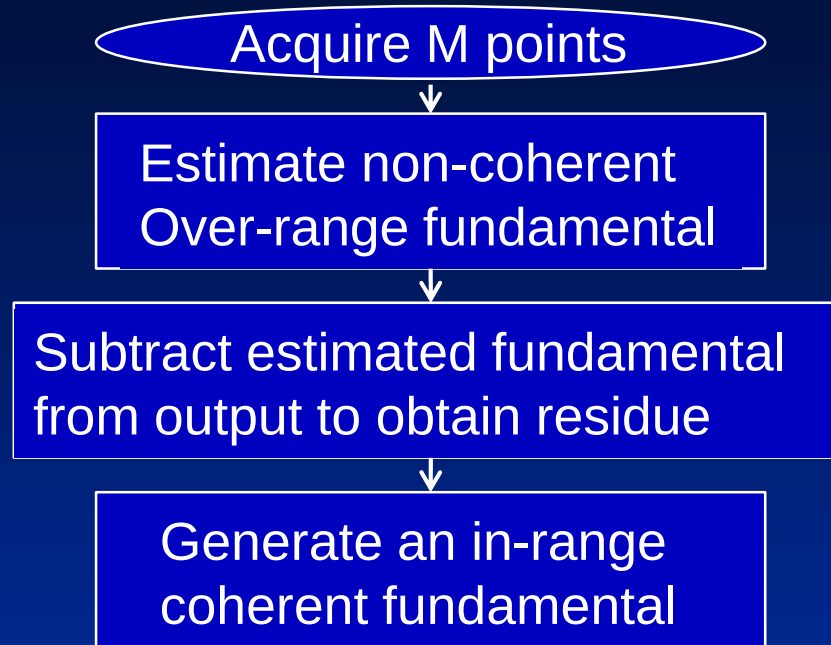
Flow Chart of FERARI



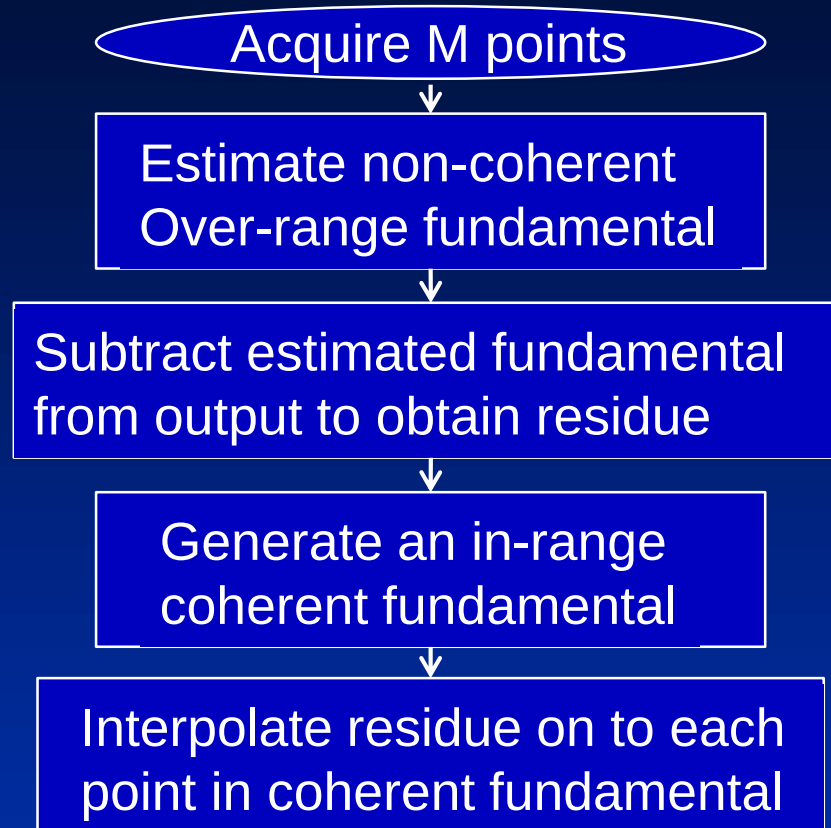
Flow Chart of FERARI



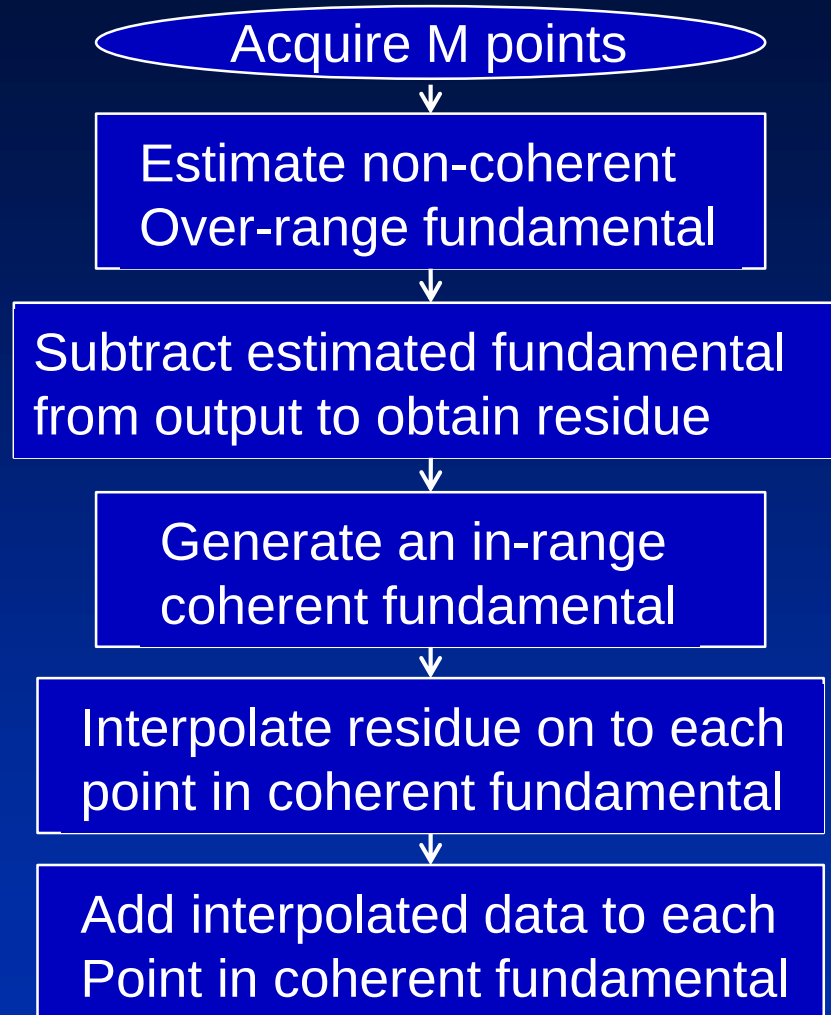
Flow Chart of FERARI



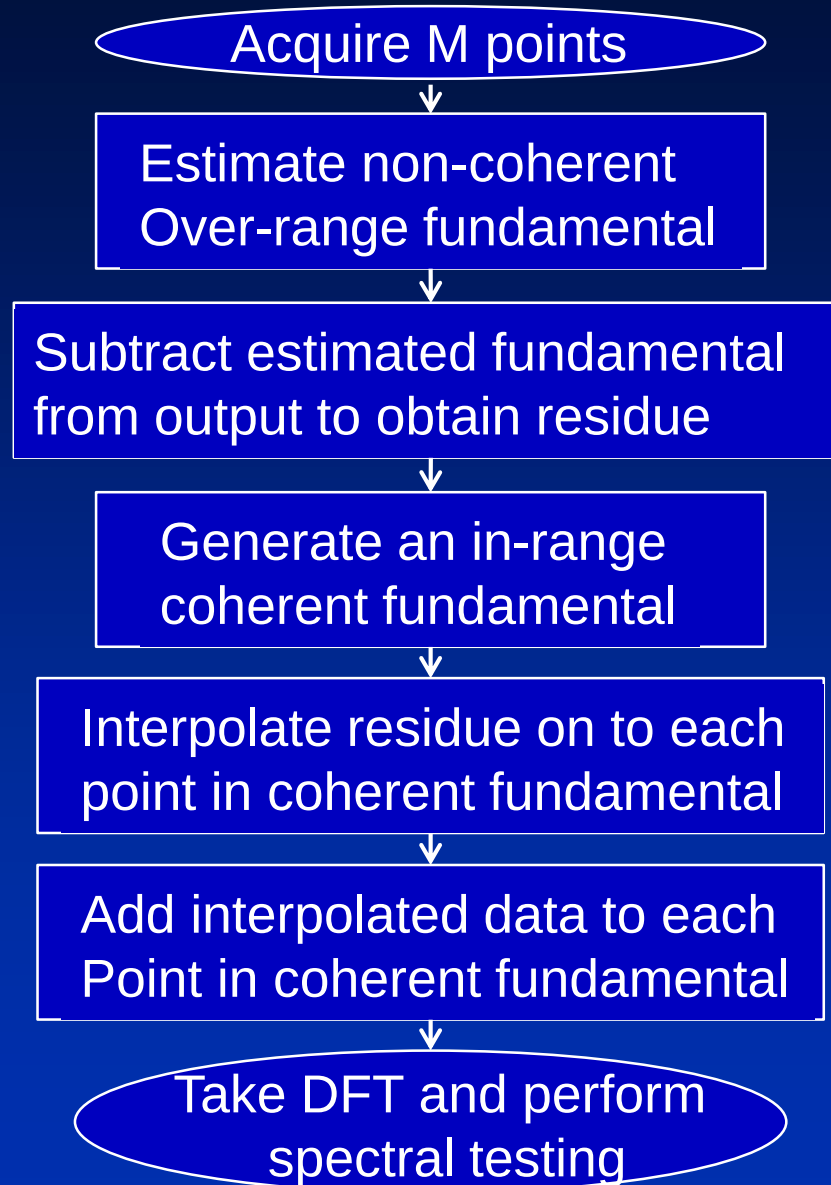
Flow Chart of FERARI



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Flow Chart of FERARI



Outline

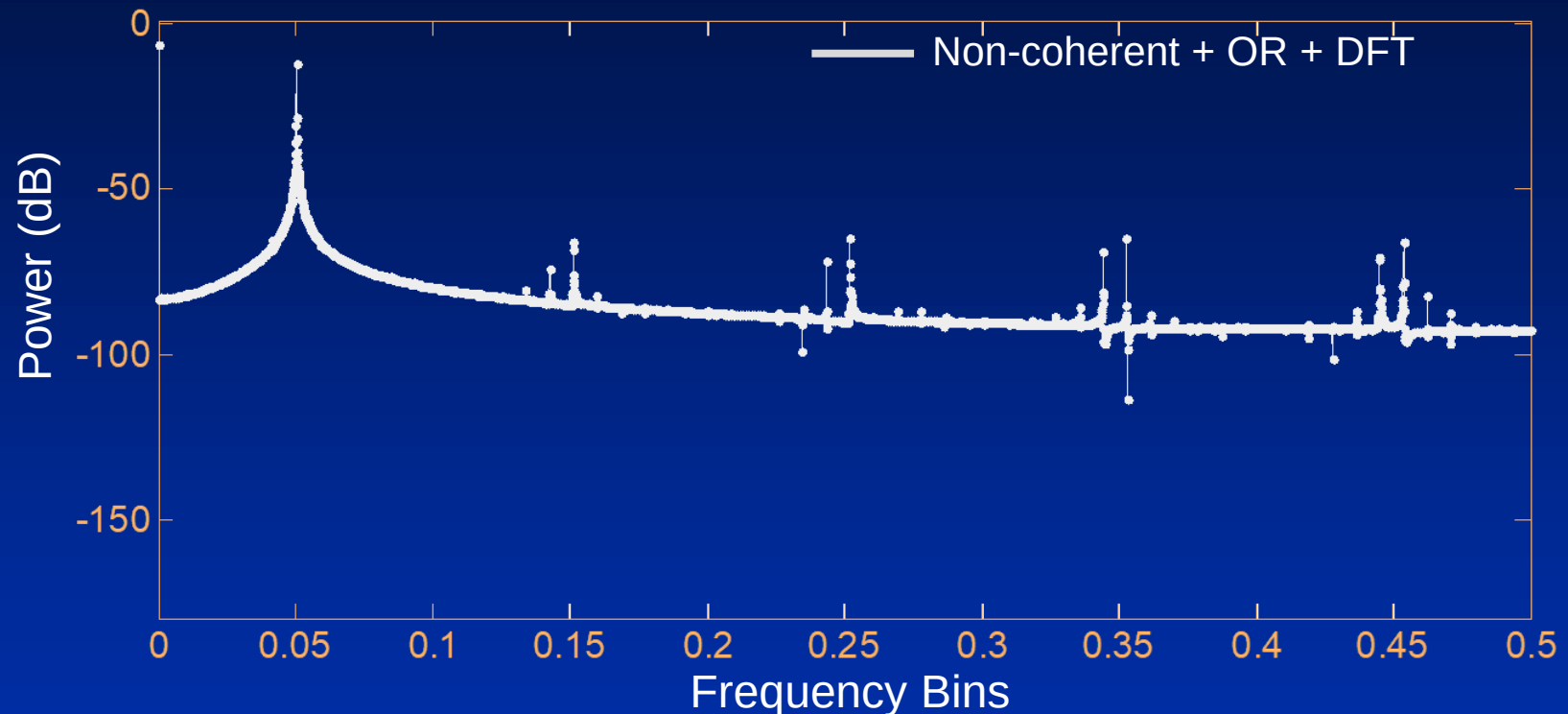
- Motivation and Spectral testing Background
- Proposed spectral testing method
 - Fundamental Estimation, Removal And Residue Interpolation (FERARI)
 - Spectral Testing Algorithm
- **Simulation Results**
- Measurement Results
- Conclusion

Simulation Results

Functionality : 16-bit ADC, INL = 0.6 LSB, M = 8192

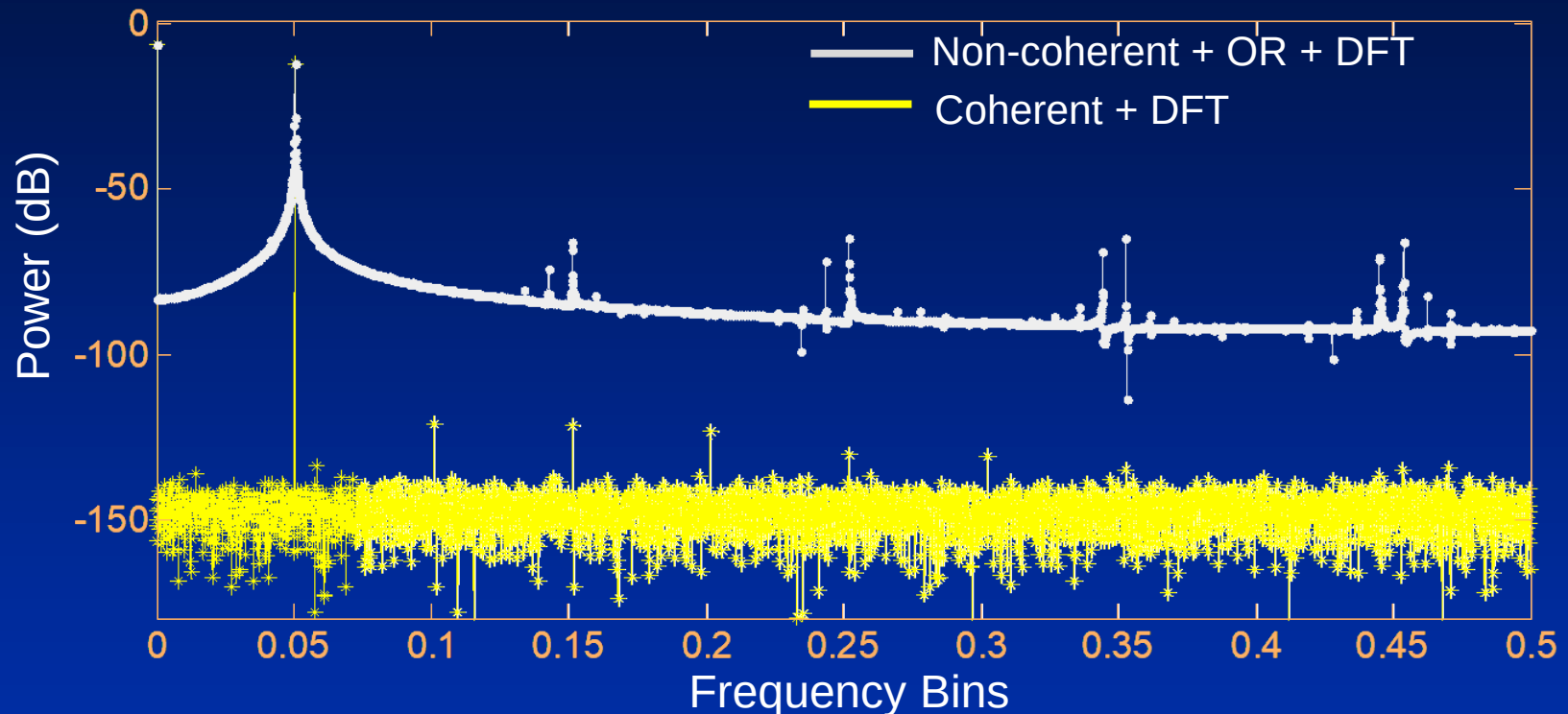
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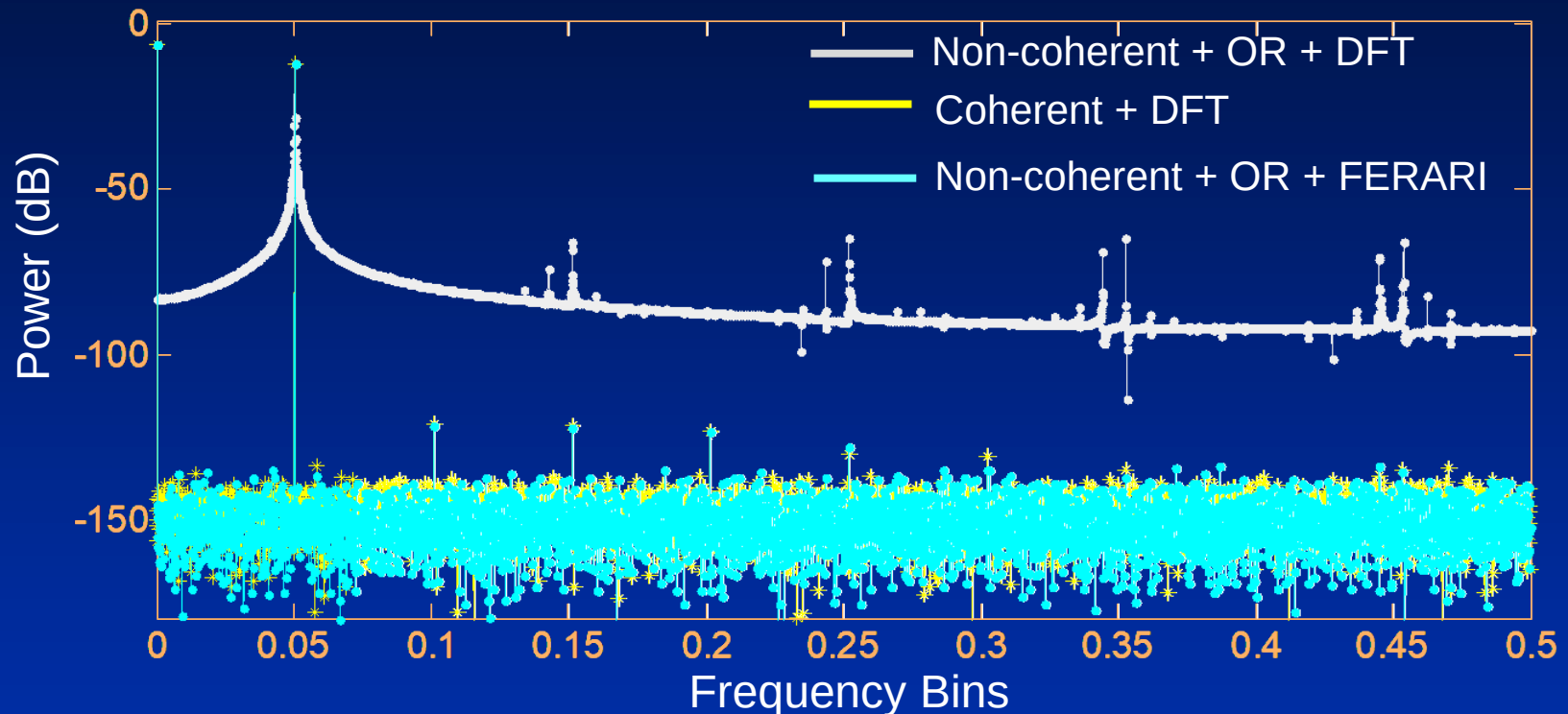
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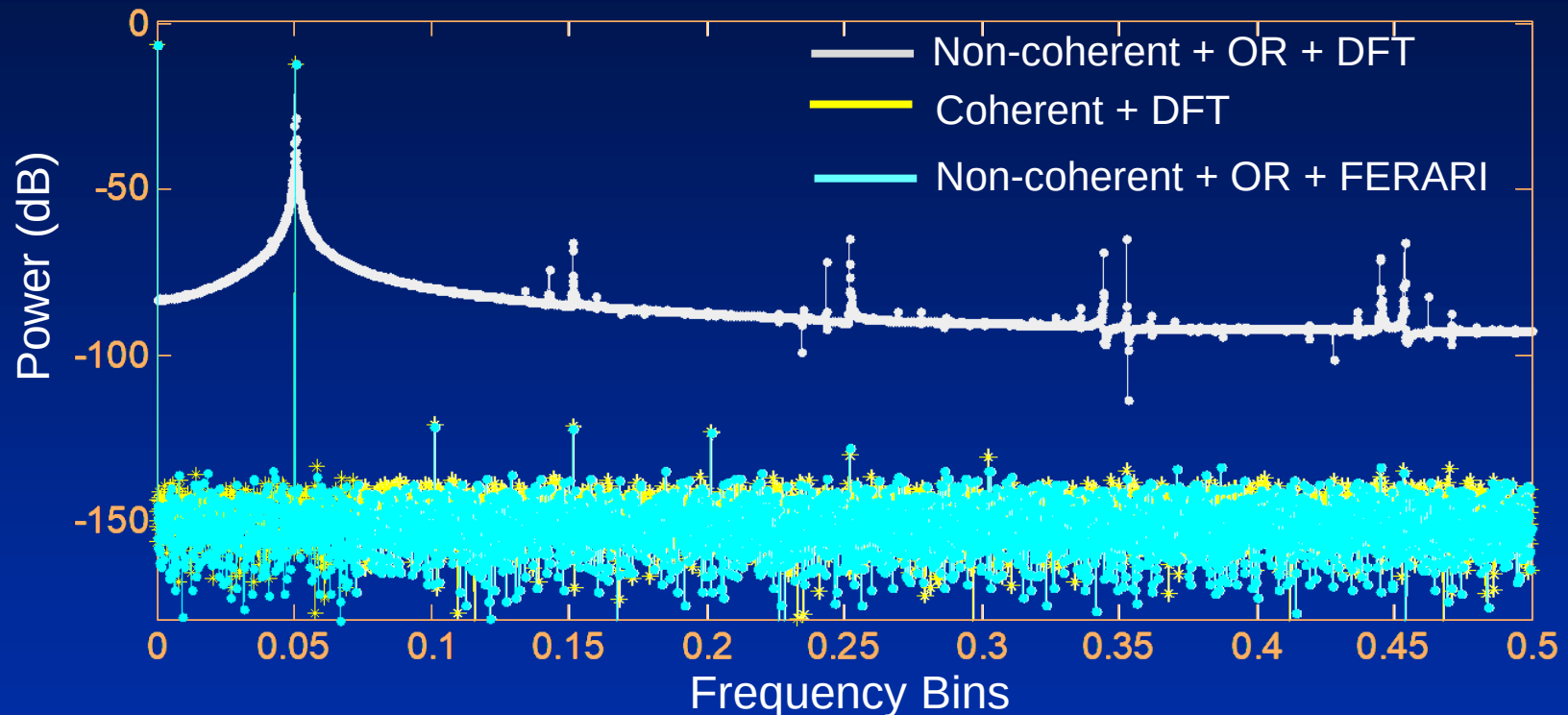
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Simulation Results

Functionality : 16-bit ADC, INL = 0.6 LSB, M = 8192



Method	% Clip	δ	THD (dB)	SFDR (dB)
Coherent + DFT	0	0	-104.2	108.6
Non-coherent + Clipping + FERARI	1.7	0.14	-104.7	109.4

Simulation Results

Robustness (w.r.t non-coherency and clipping)

16-bit ADC, INL = 1.8LSB, M = 8192

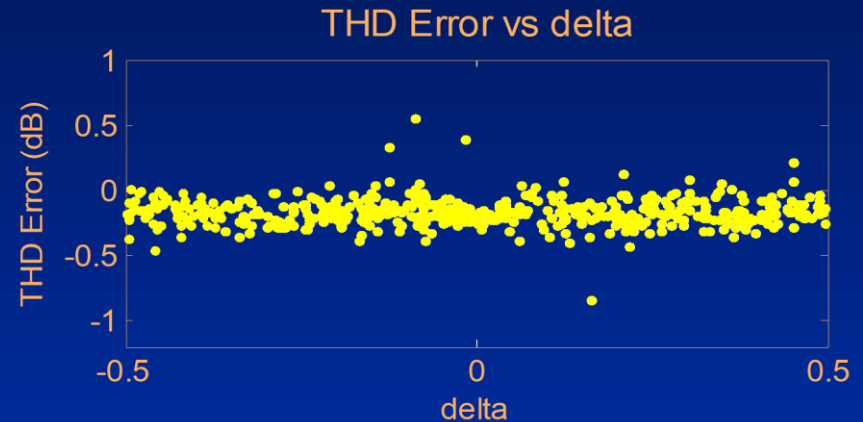
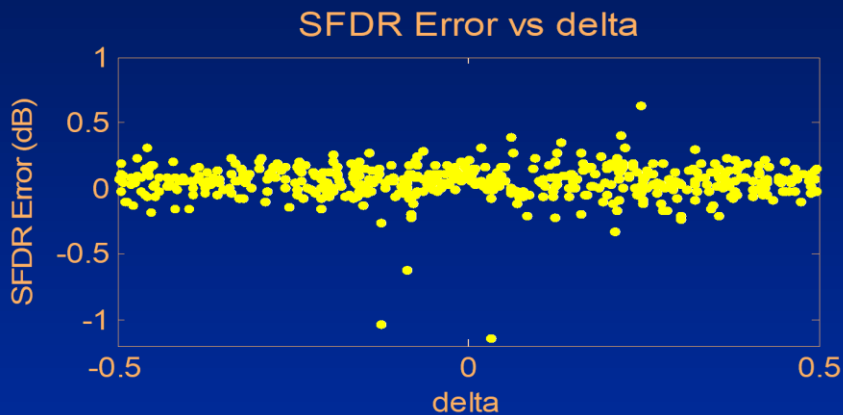
δ range = -0.5 to 0.5; % amplitude over-range = 0 to 2

Simulation Results

Robustness (w.r.t non-coherency and clipping)

16-bit ADC, INL = 1.8LSB, M = 8192

δ range = -0.5 to 0.5; % amplitude over-range = 0 to 2

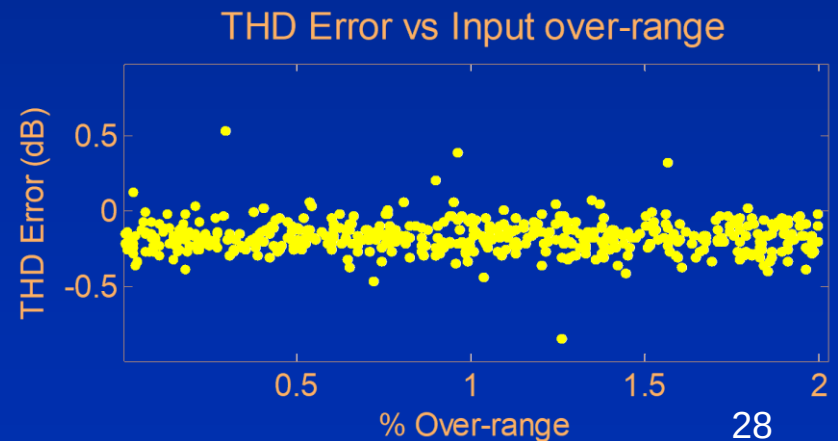
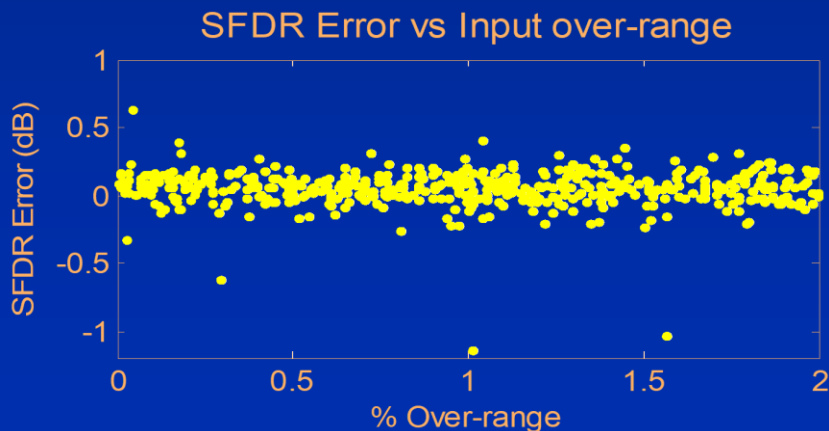
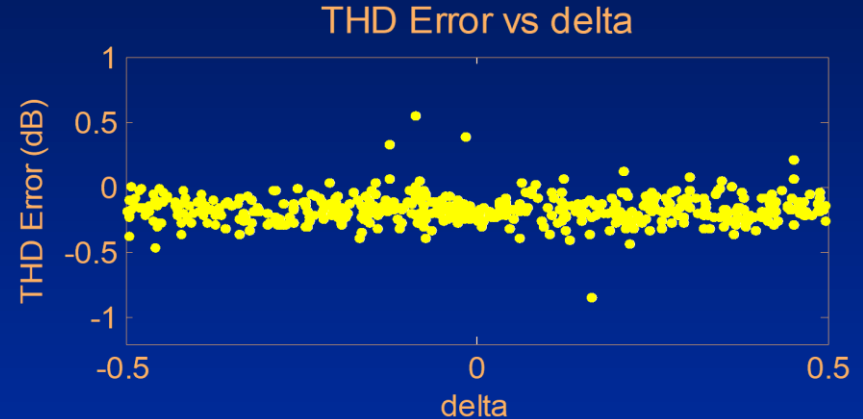
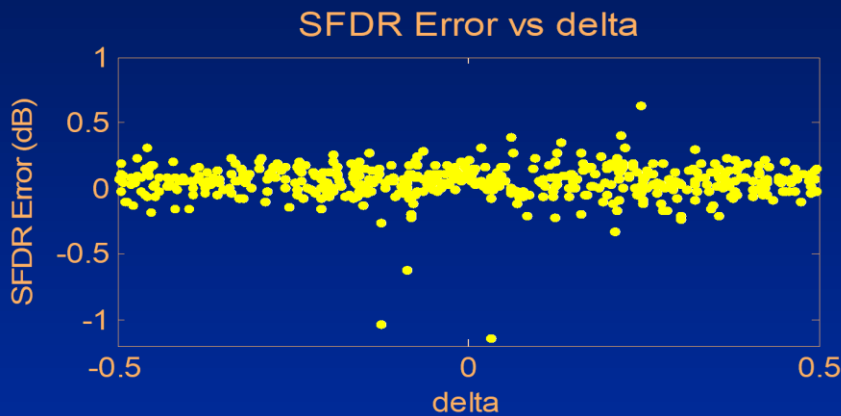


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Use of interpolation (Varying over-range)

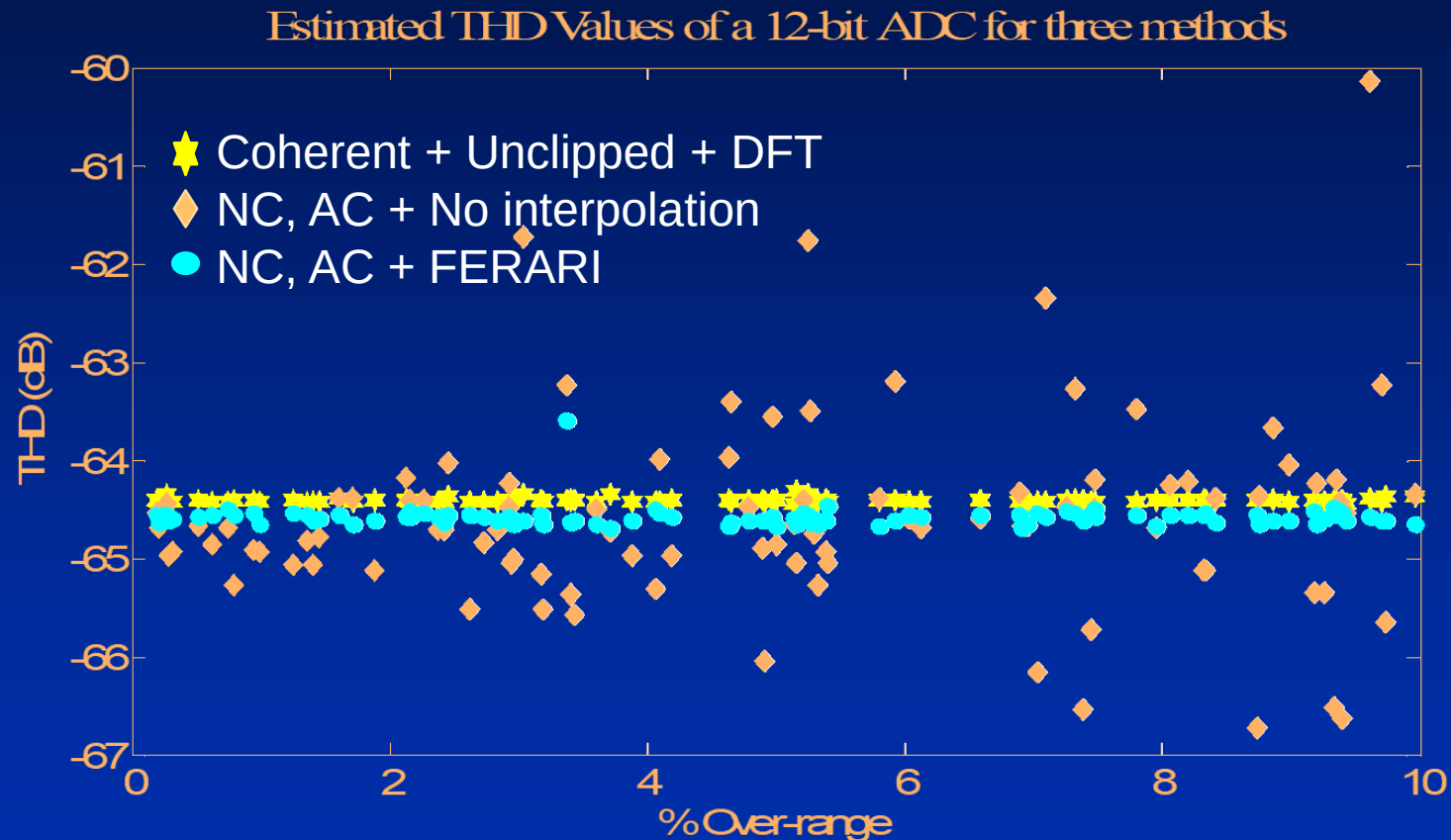
ADC resolution = 12

Input over-range : From 0 to 10%

Use of interpolation (Varying over-range)

ADC resolution = 12

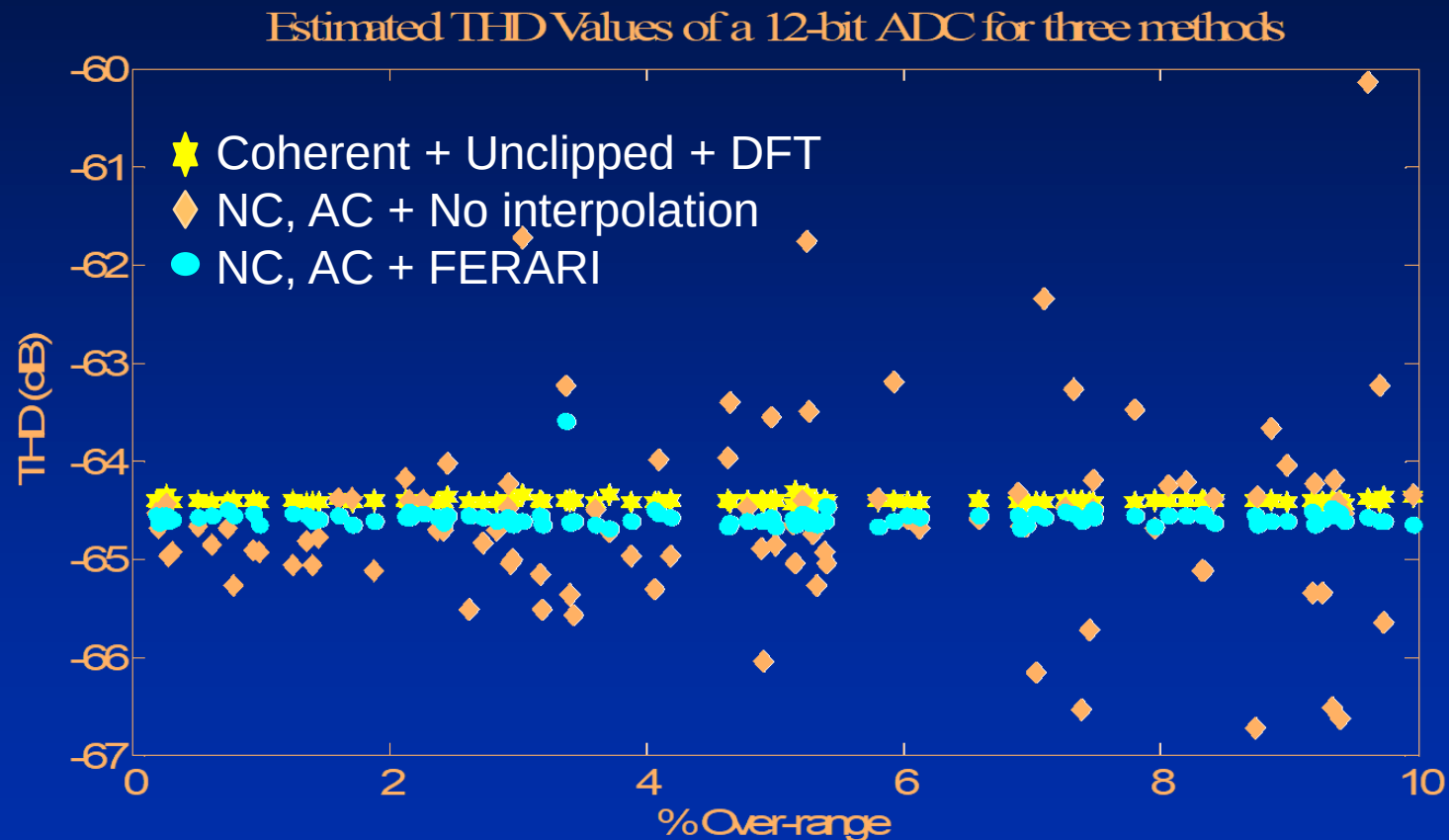
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Use of interpolation (Varying over-range)

ADC resolution = 12

Input over-range : From 0 to 10%



Interpolation required for accurate results

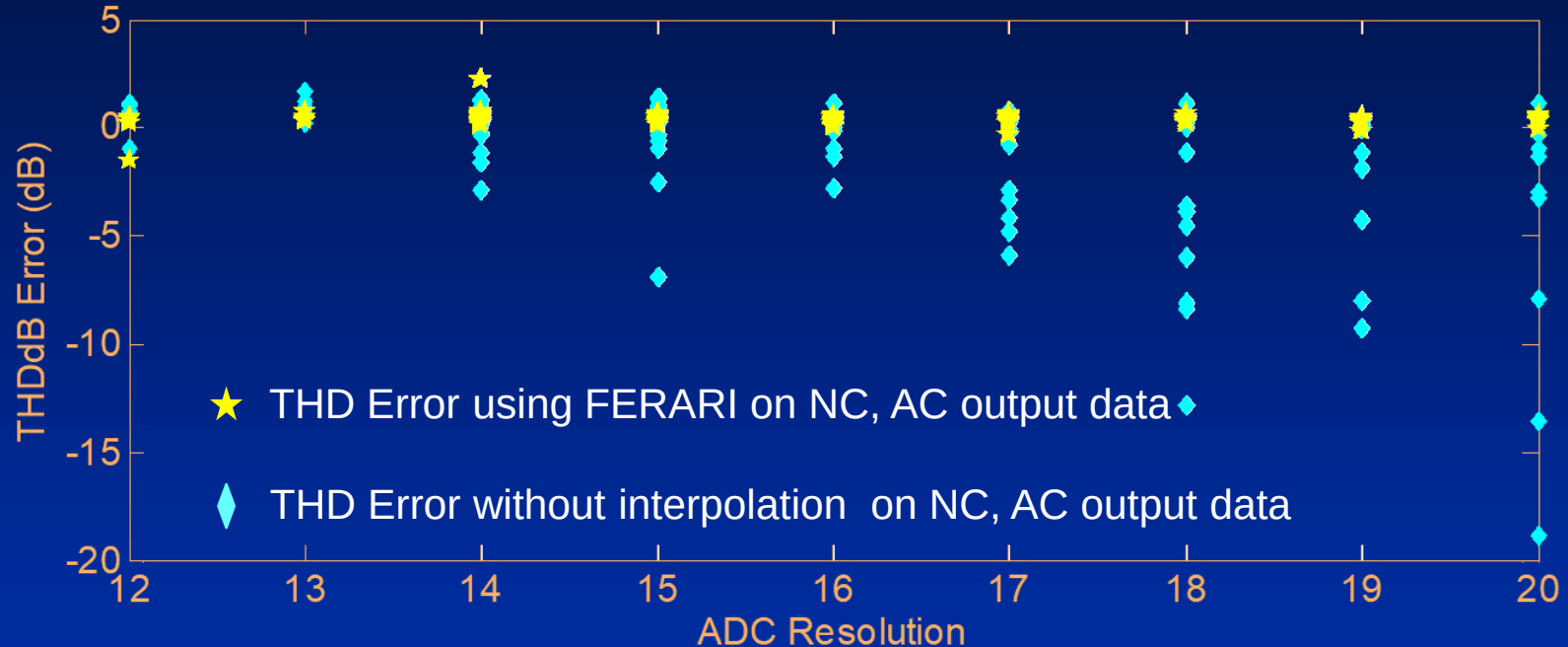
Use of interpolation (Varying resolution)

ADC resolution = From 12 to 20 bits; Input over-range = 1.9%

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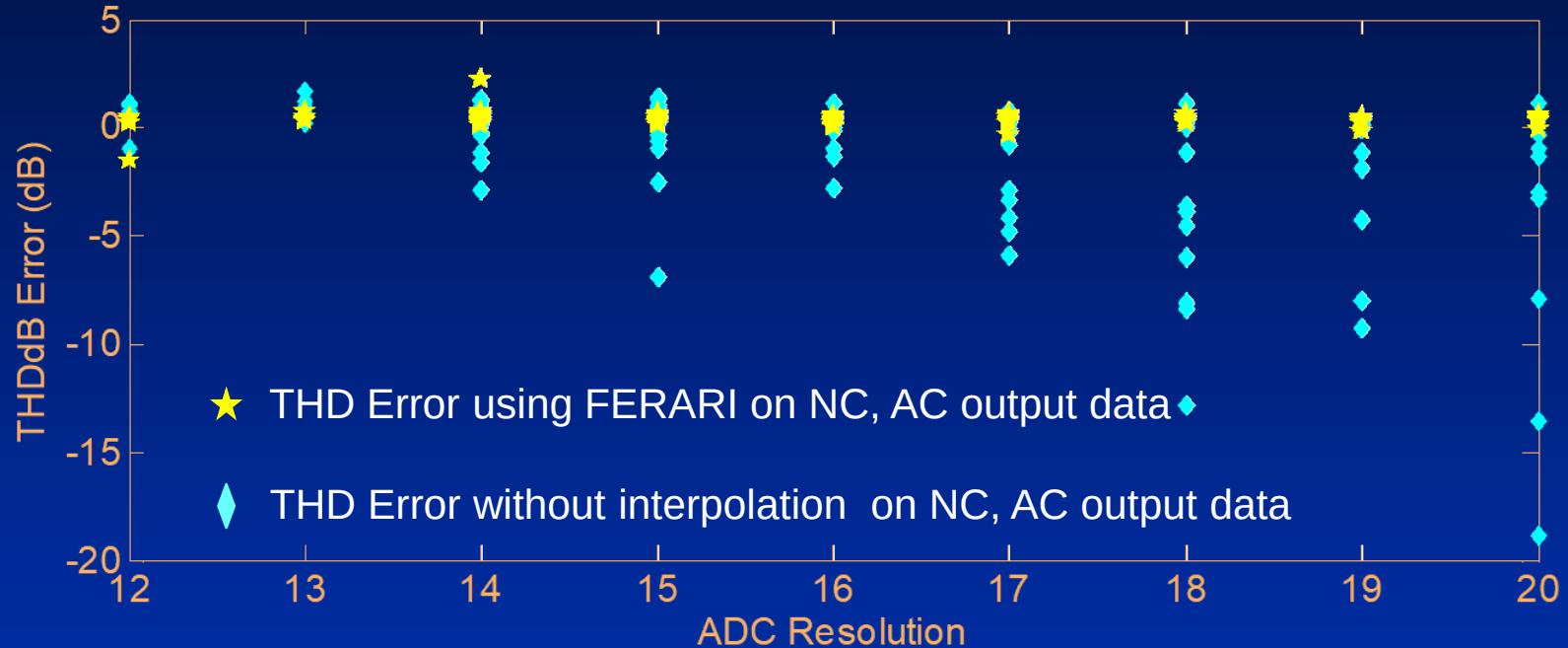
THD Error obtained with / without interpolation
for a 1.9% over-ranged input for different ADCs



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ADC resolution = From 12 to 20 bits; Input over-range = 1.9%

THD Error obtained with / without interpolation
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Low resolution, 12-bit (1.7% over-range)

High resolution, 18-bit (1.7% over-range)

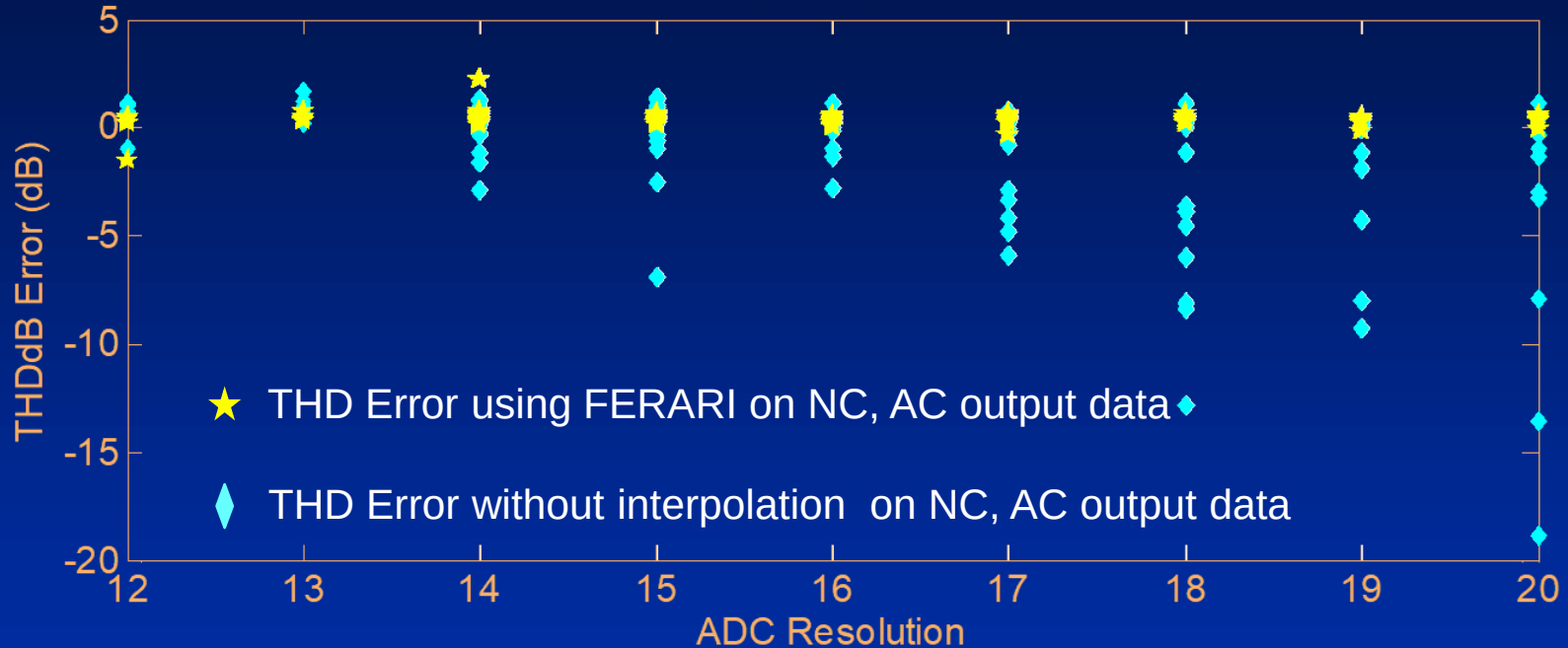
Method	THD (dB)	SFDR (dB)
Coherent Unclipped (Reference)	-70.3	73.9
NC, AC + No residue interpolation	-70.5	74.7
NC, AC + FERARI	-70.8	74.3

Method	THD (dB)	SFDR (dB)
Coherent Unclipped (Reference)	-93.1	97.7
NC, AC + No residue interpolation	-79.7	84.2
NC, AC + FERARI	-93.3	97.7

Use of interpolation (Varying resolution)

ADC resolution = From 12 to 20 bits; Input over-range = 1.9%

THD Error obtained with / without interpolation
for a 1.9% over-ranged input for different ADCs



Low resolution, 12-bit (1.7% over-range)

Method	THD (dB)	SFDR (dB)
Coherent Unclipped (Reference)	-70.3	73.9
NC, AC + No residue interpolation	-70.5	74.7
NC, AC + FERARI	-70.8	74.3

High resolution, 18-bit (1.7% over-range)

Method	THD (dB)	SFDR (dB)
Coherent Unclipped (Reference)	-93.1	97.7
NC, AC + No residue interpolation	-79.7	84.2
NC, AC + FERARI	-93.3	97.7

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Measurement Results

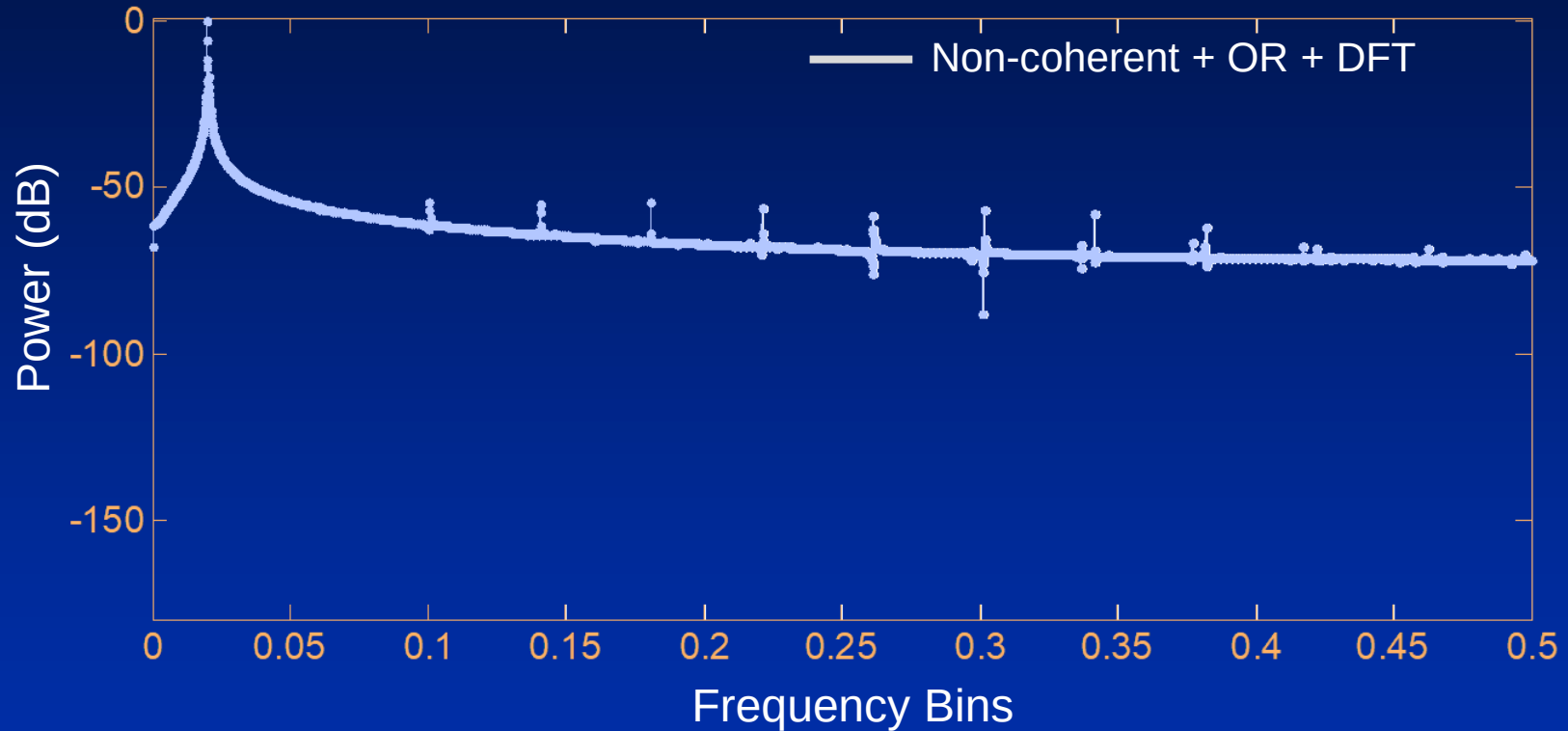
Functionality : 16-bit SAR ADC, ADS8318

$\delta = -0.35$, %OR = 1.5

Measurement Results

Functionality : 16-bit SAR ADC, ADS8318

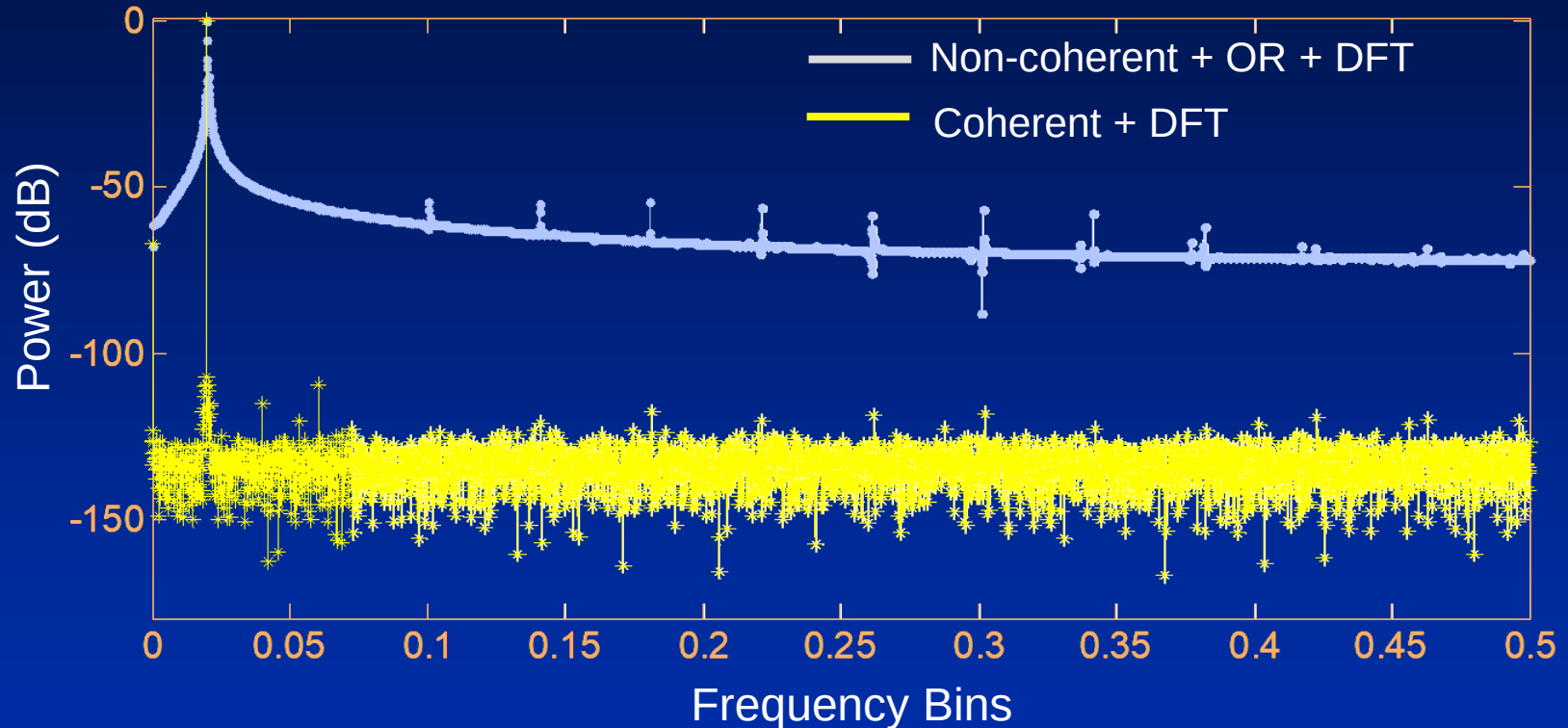
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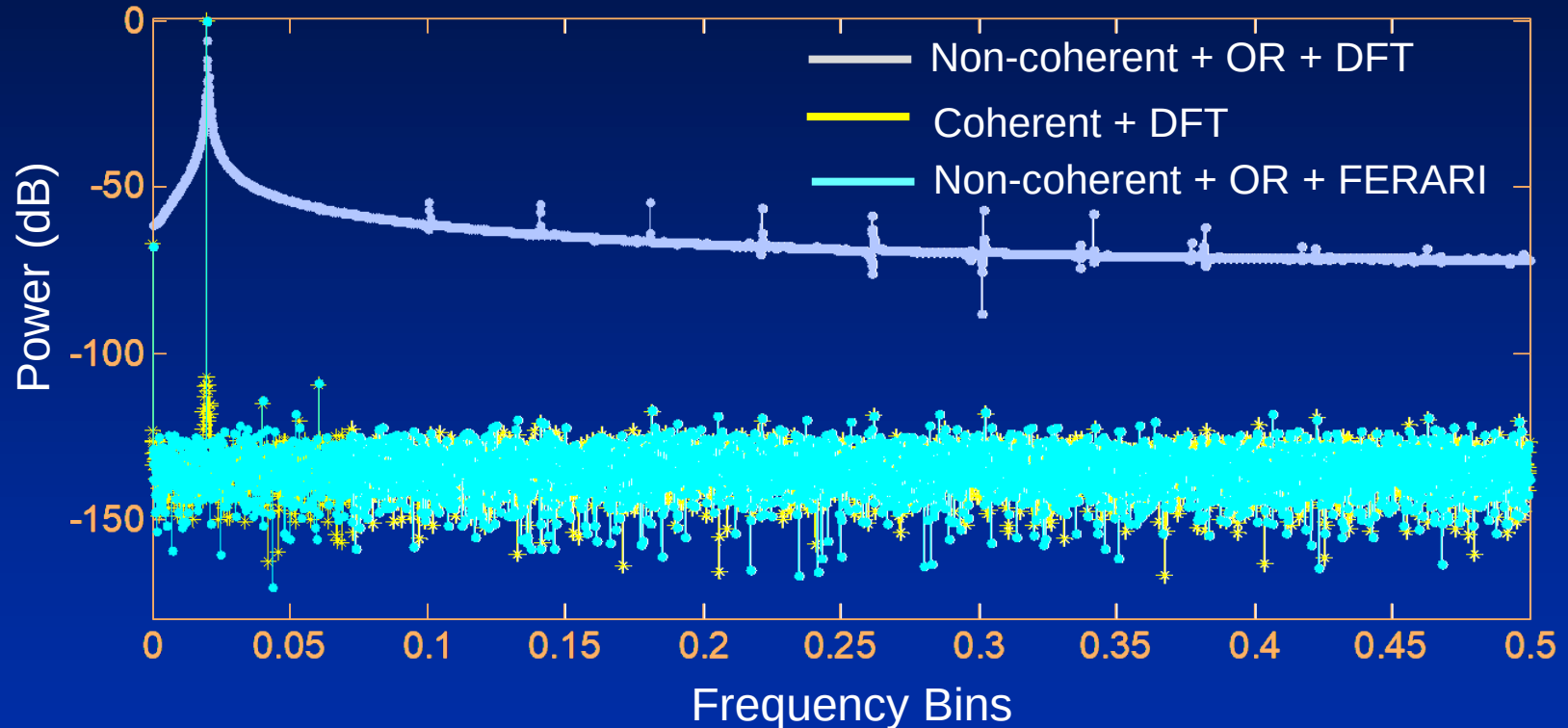
$\delta = -0.35$, %OR = 1.5



Measurement Results

Functionality : 16-bit SAR ADC, ADS8318

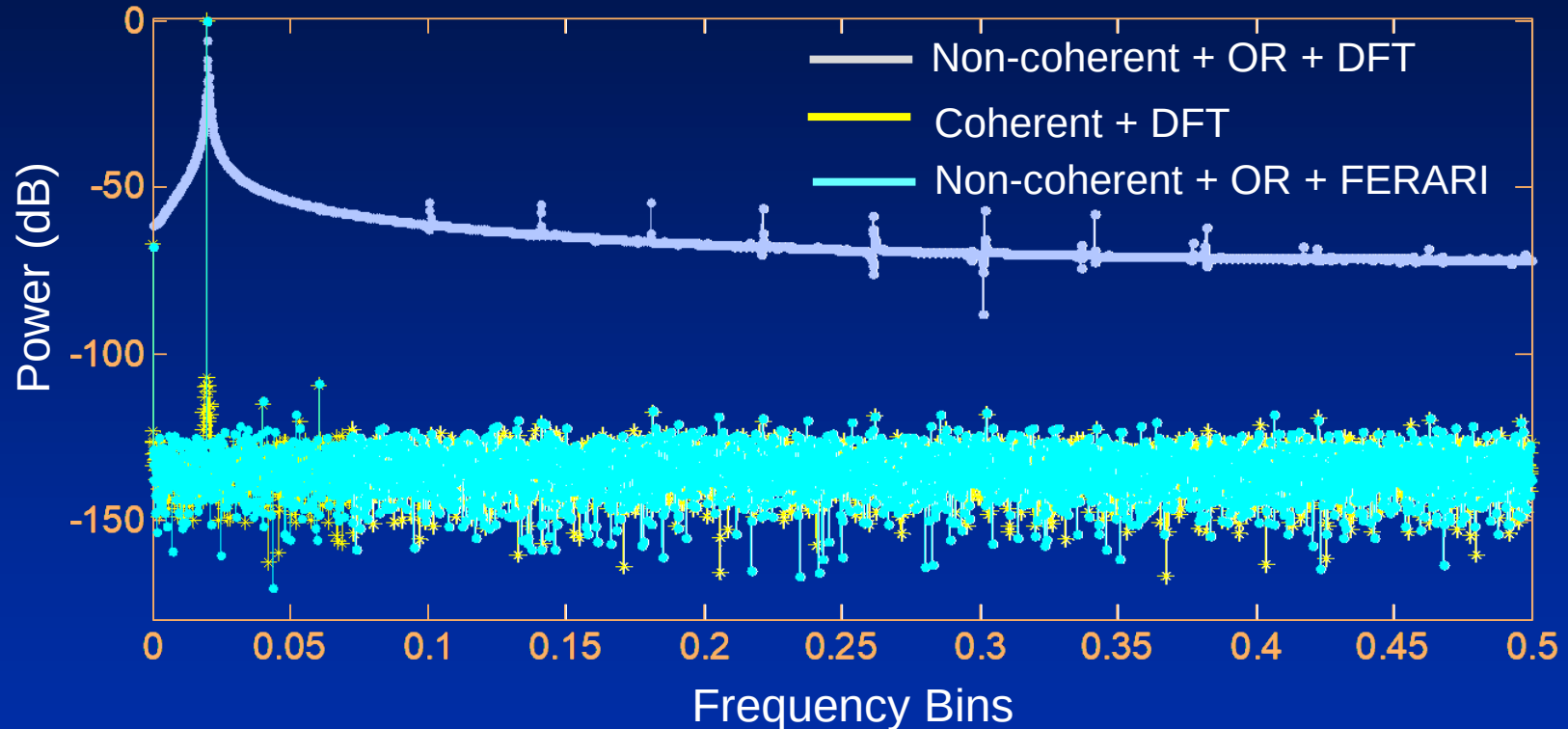
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Measurement Results

Functionality : 16-bit SAR ADC, ADS8318

$\delta = -0.35$, %OR = 1.5



Method	% Clip	THD (dB)	SFDR (dB)	SNR (dB)
Coherent	0	-107.5	108.5	95.8
Non-coherent +Clipping	1.5	-108.1	109.2	95.8

ADS8318

16-bit SAR

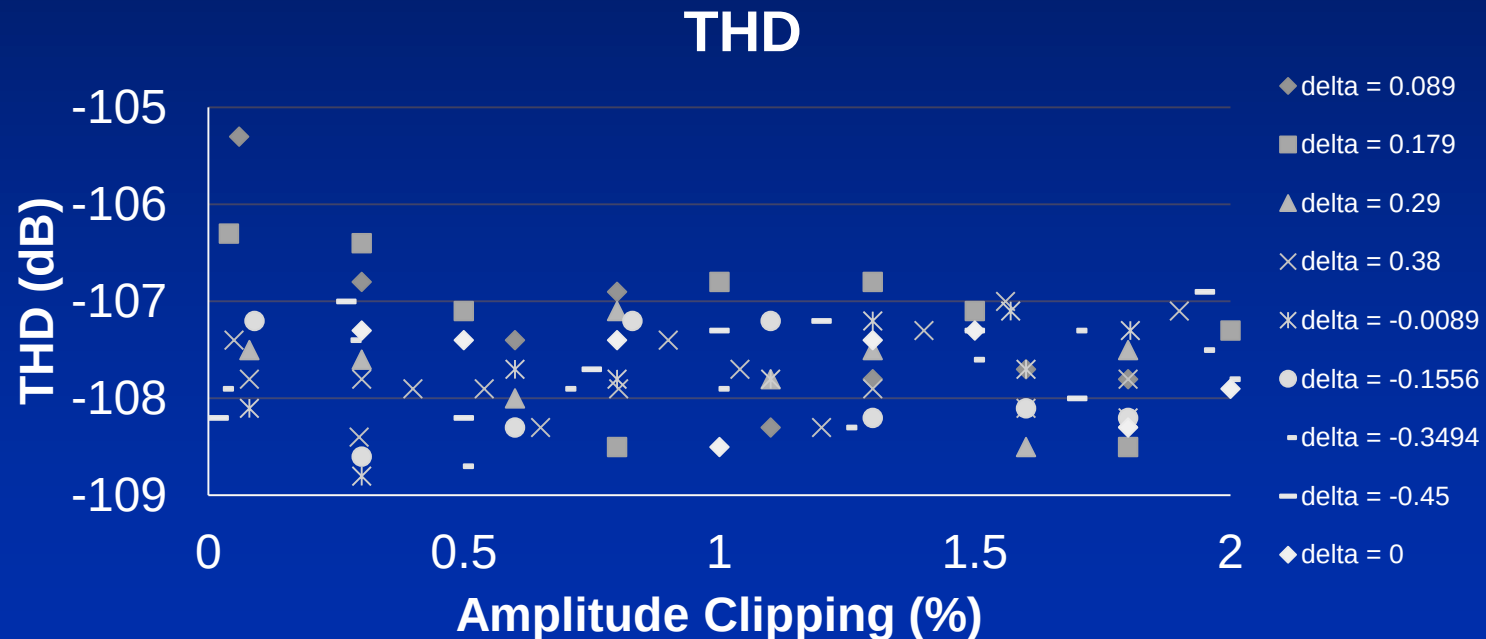
Signal frequency in the range of 10kHz (Varies with value of δ)

$f_{\text{Samp}} = 500\text{kSPS}$, $M = 8192$

Amplitude Clipping : 0-2% linear range

Non-coherency: -0.5 to 0.5

THD coherent = -107.5dB



ADS8318

16-bit SAR

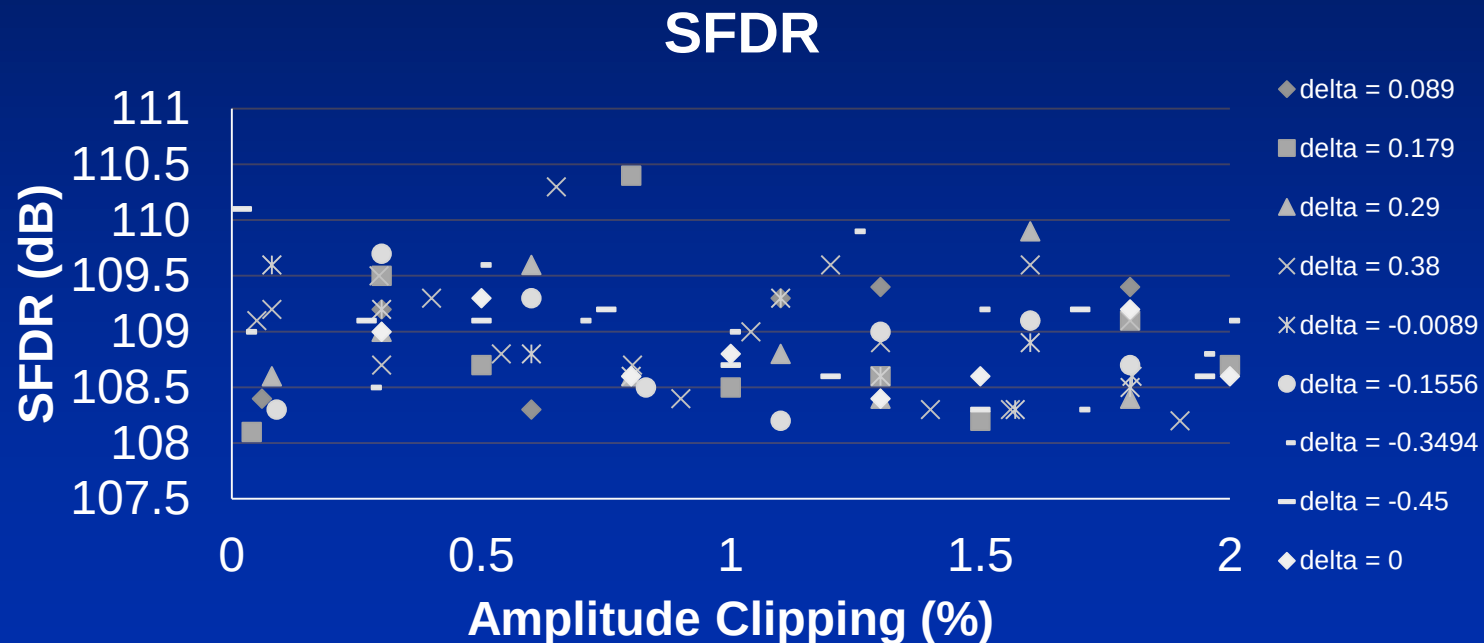
Signal frequency in the range of 10kHz (Varies with value of δ)

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Amplitude Clipping : 0-2% linear range

Non-coherency: -0.5 to 0.5

SFDR coherent = 108.5dB



ADS8318

16-bit SAR

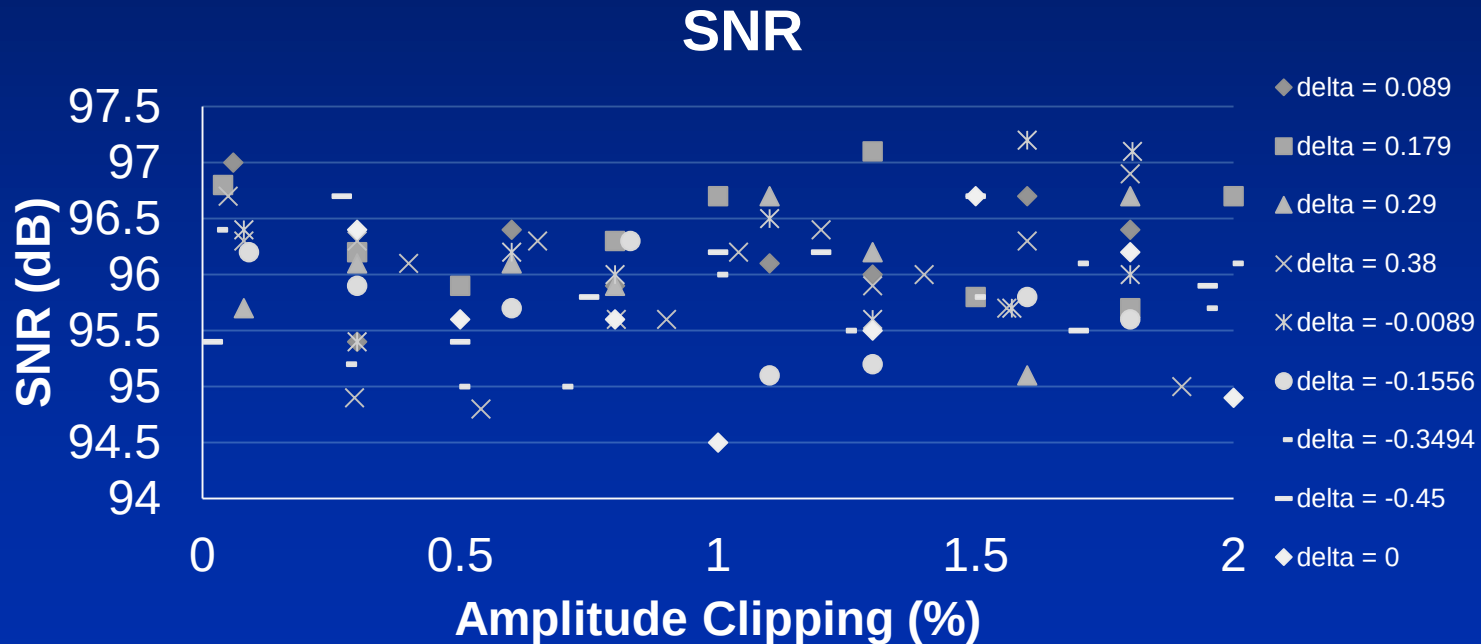
Signal frequency in the range of 10kHz (Varies with value of δ)

$f_{\text{Samp}} = 500\text{kSPS}$, $M = 8192$

Amplitude Clipping : 0-2% linear range

Non-coherency: -0.5 to 0.5

SNR coherent = 95.8dB



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Conclusion

- Proposed new test method
 - Non-coherent sampling and amplitude clipping
- Fundamental identification
 - Using both time and frequency domain data
- Accurate functionality and robustness verified
 - Simulation and measurement data
- Applicable for BIST ADCs where precise amplitude and frequency control is challenging

Thank You